

EECS151/251A

Spring 2018

Digital Design and Integrated Circuits

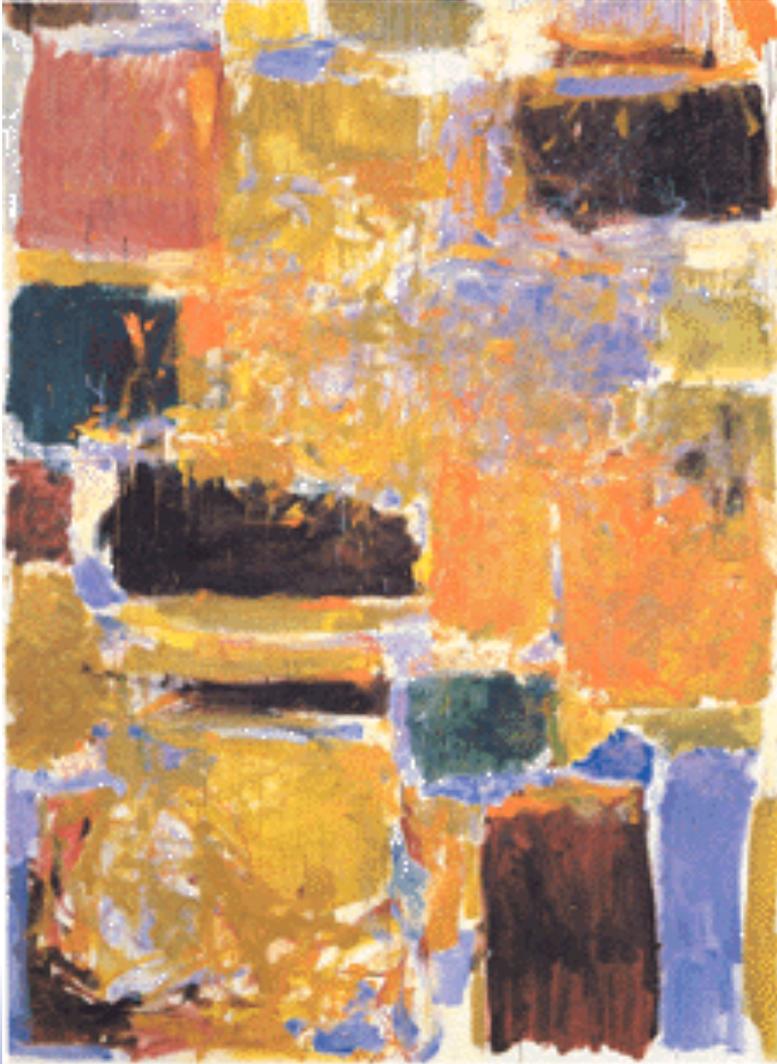
Instructors:

John Wawrzynek and Nick Weaver

Lecture 25:

Clock and Power Distribution

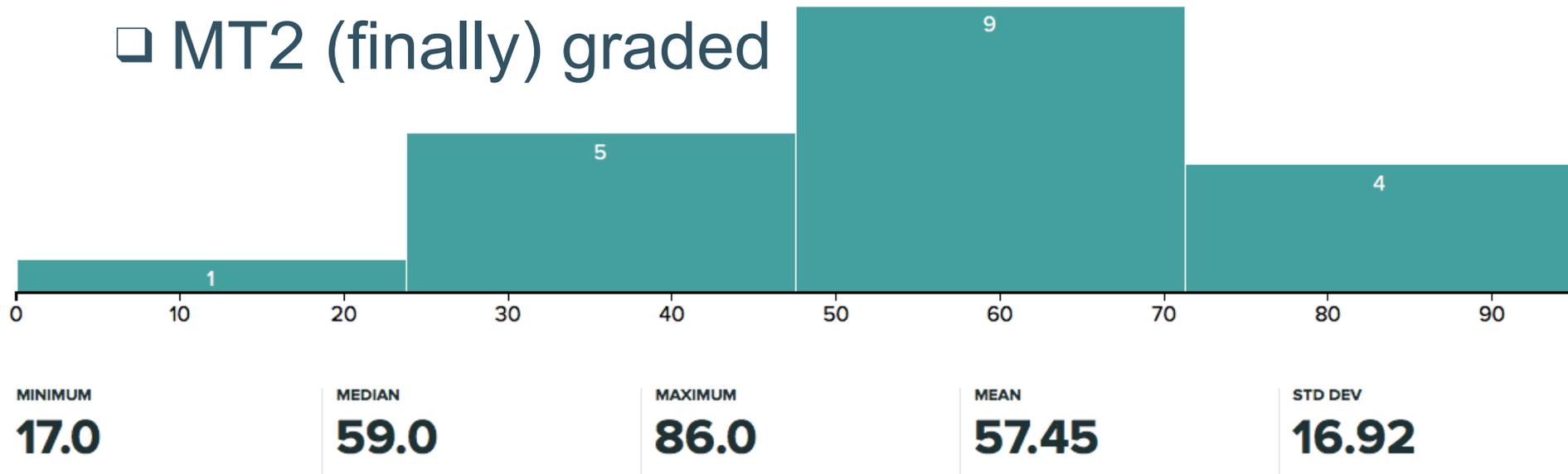
Outline



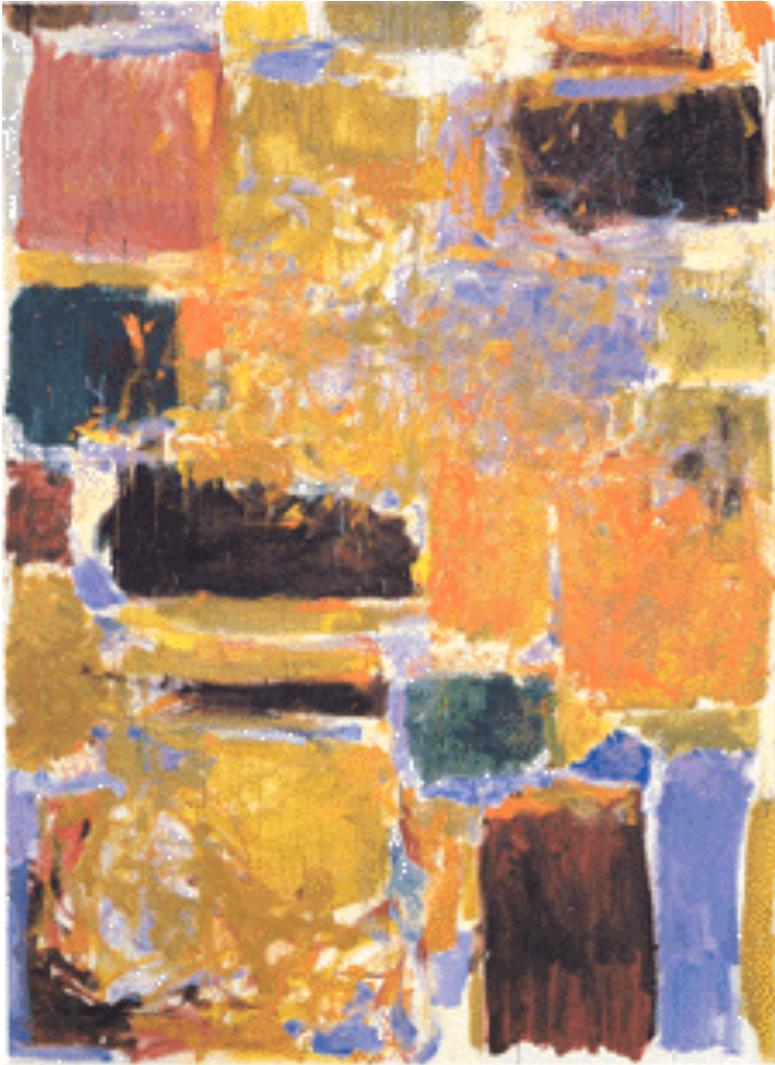
- ❑ Clock non-idealities
- ❑ Clock Distribution
- ❑ Chip Packaging
- ❑ Power Distribution

Administrative

- MT2 (finally) graded

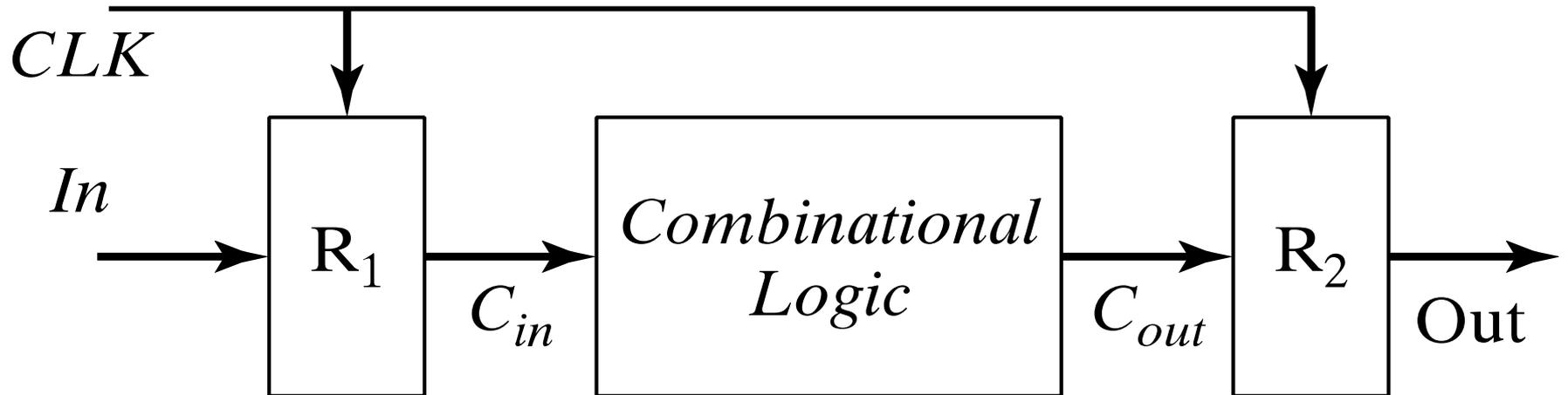


- Final Project demo/interview
 - Friday 5/4 afternoon - signup for slot

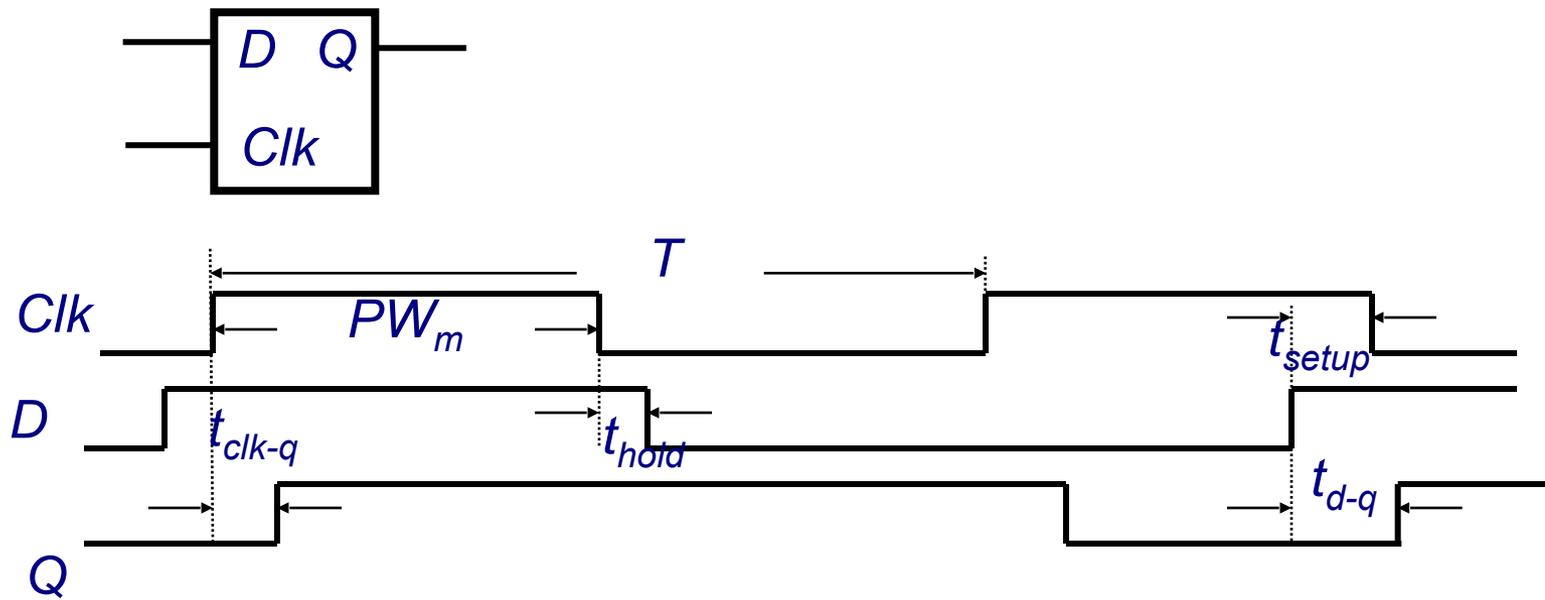


Synchronous Timing - Review

Synchronous Timing

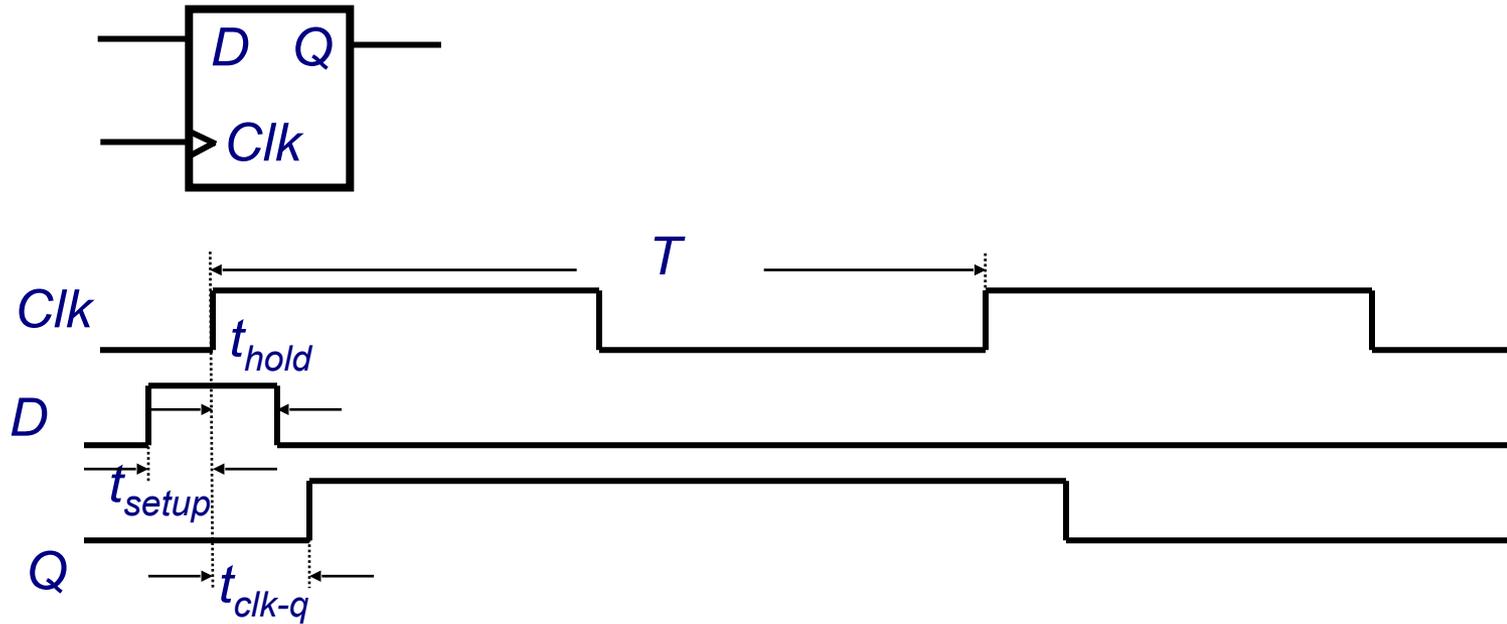


Latch Parameters



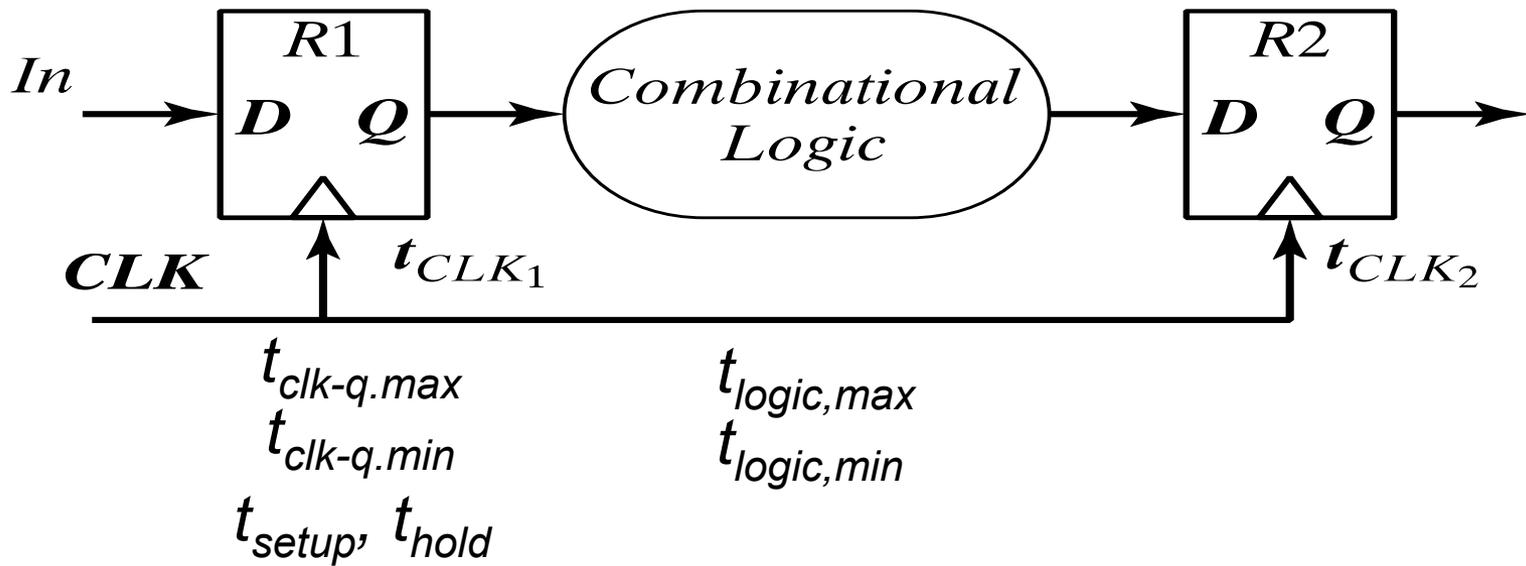
Delays can be different for rising and falling data transitions

Register Parameters

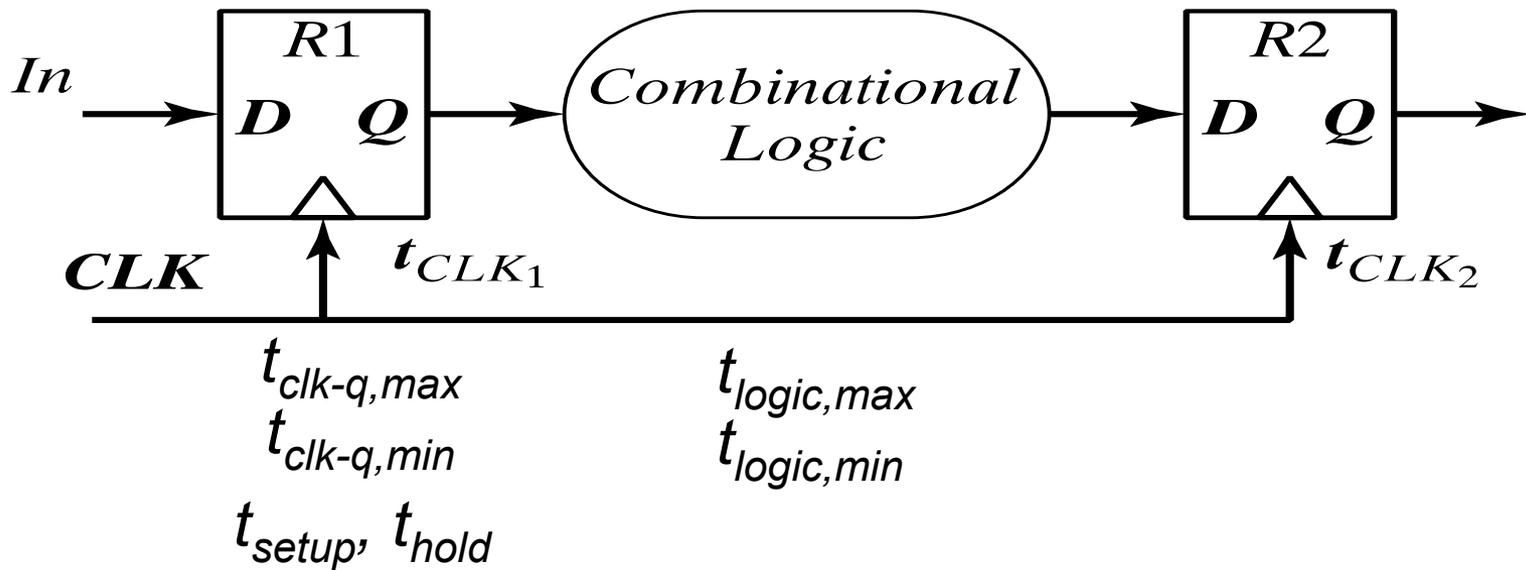


Delays can be different for rising and falling data transitions

Timing Constraints

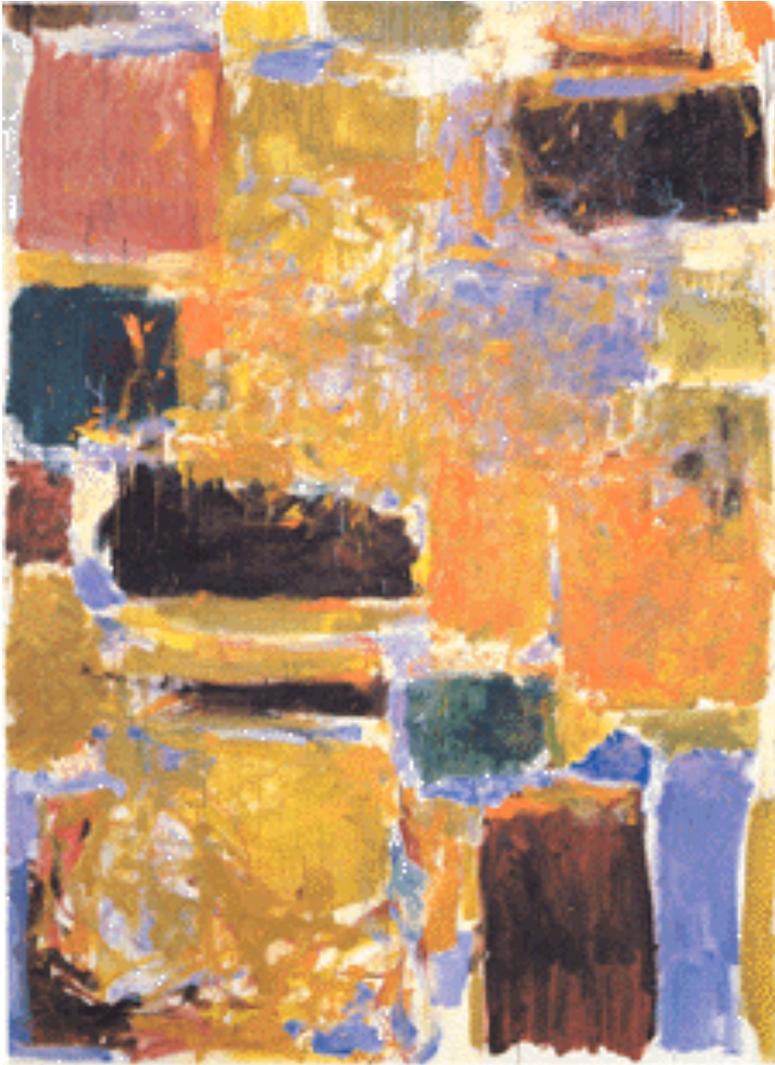


Timing Constraints



Cycle time (max): $T_{clk} > t_{clk-q,max} + t_{logic,max} + t_{setup}$

Race margin (min): $t_{hold} < t_{clk-q,min} + t_{logic,min}$



Clock Nonidealities

Clock Nonidealities

□ Clock skew

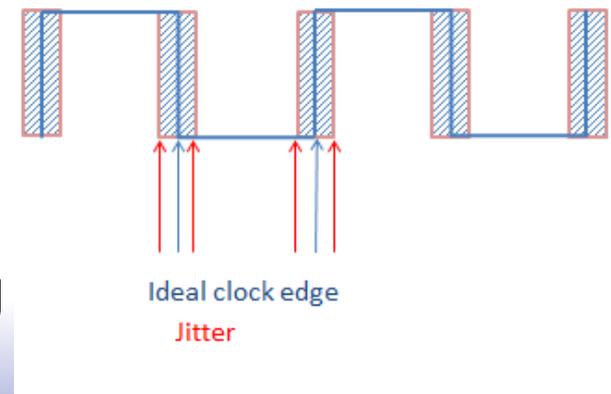
- Time difference between the sink (receiving) and source (launching) edge
- Spatial variation in temporally equivalent clock edges; deterministic + random, t_{SK}

□ Clock jitter

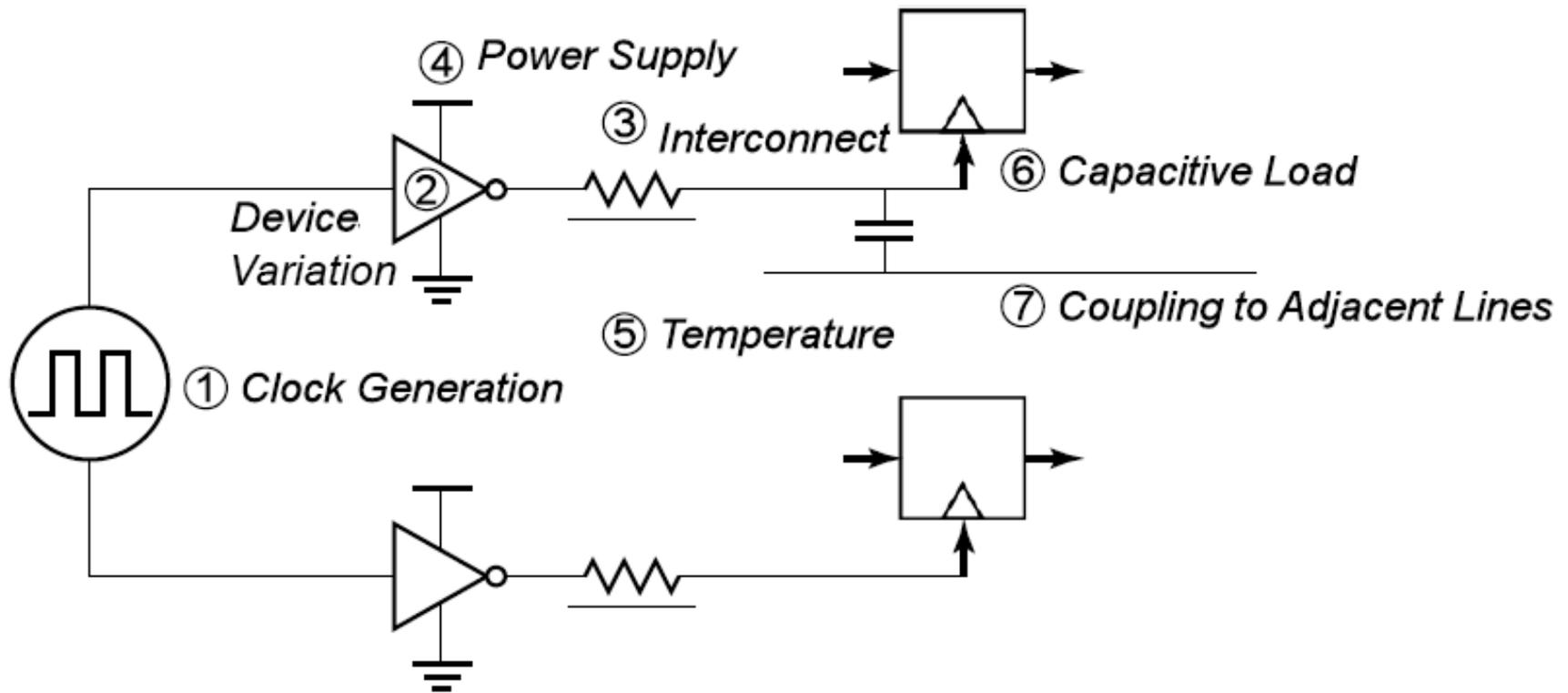
- Temporal variations in consecutive edges of the clock signal; modulation + random noise
- Cycle-to-cycle (short-term) t_{JS}
- Long term t_{JL}

□ Variation of the pulse width

- Important for level sensitive clocking

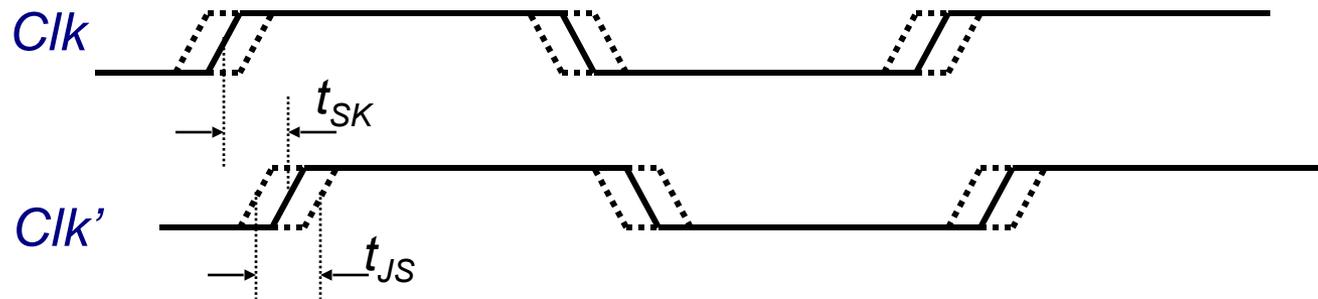


Clock Uncertainties



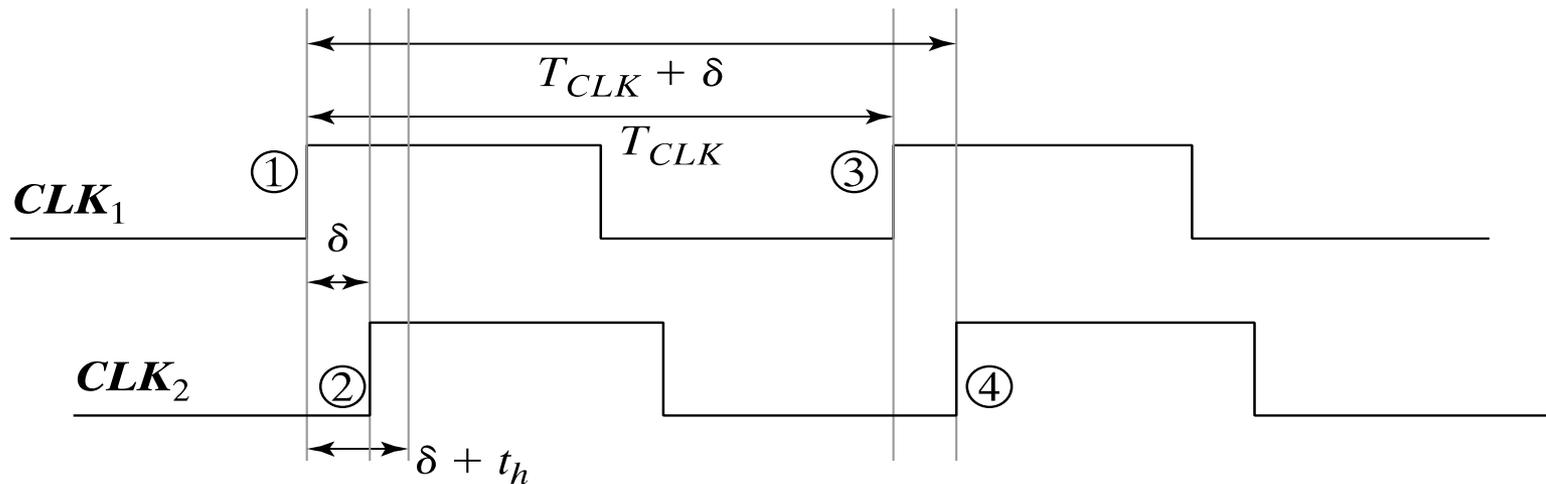
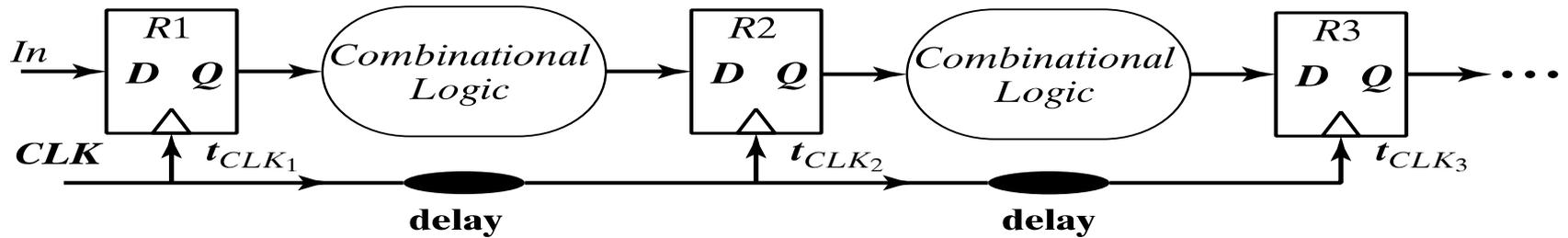
Sources of clock uncertainty

Clock Skew and Jitter



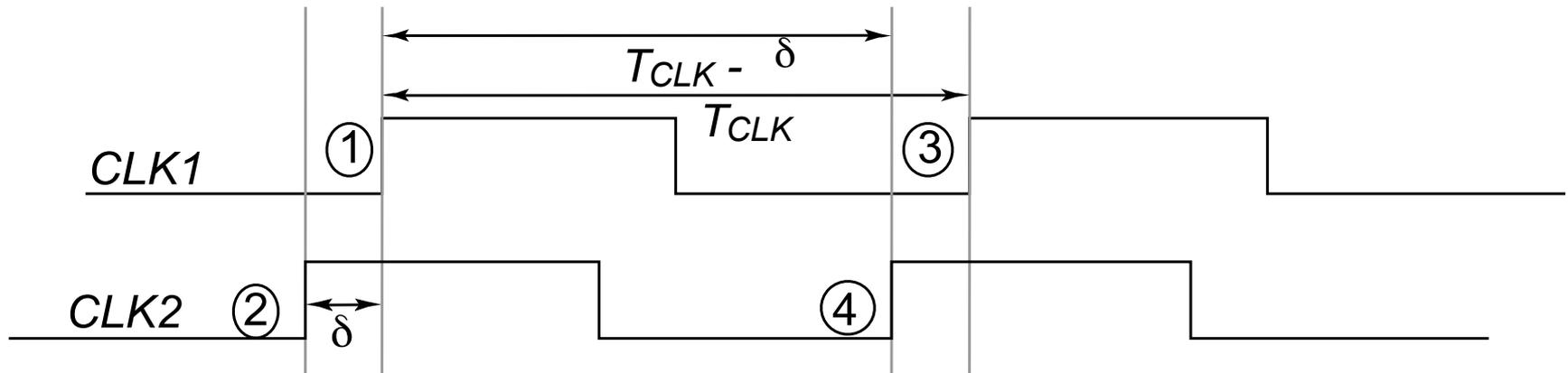
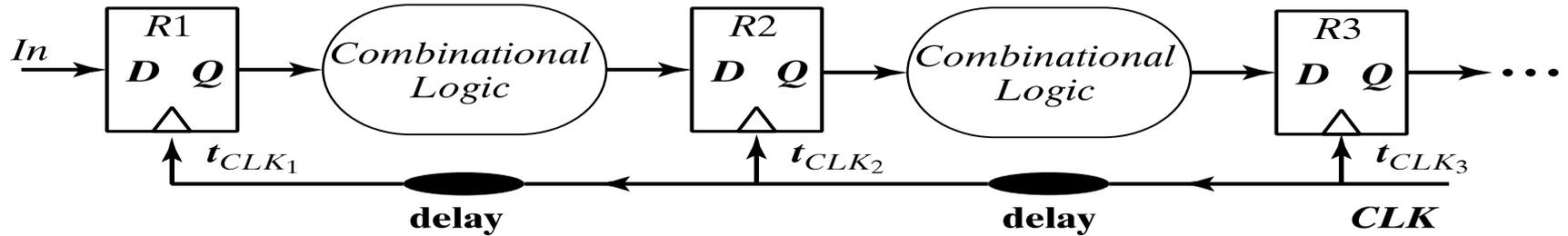
- Both skew and jitter affect the effective cycle time and the race margin

Positive Skew



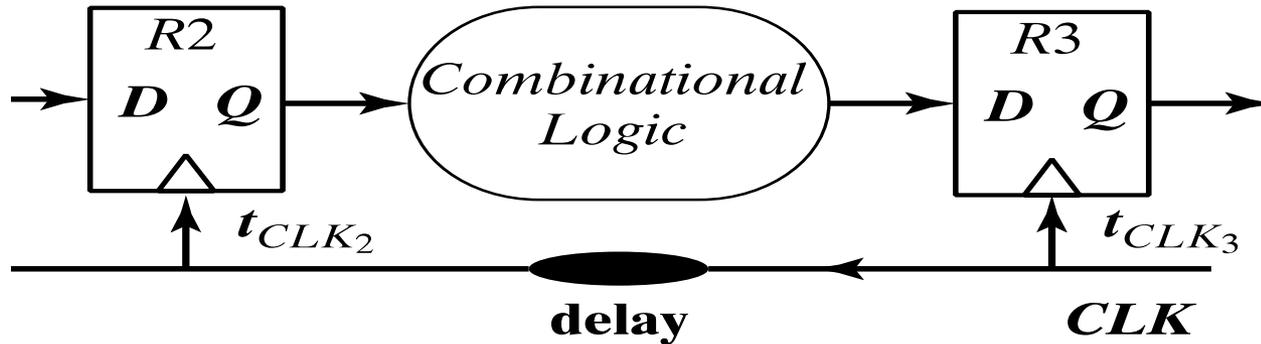
Launching edge arrives before the receiving edge

Negative Skew



Receiving edge arrives before the launching edge

Timing Constraints



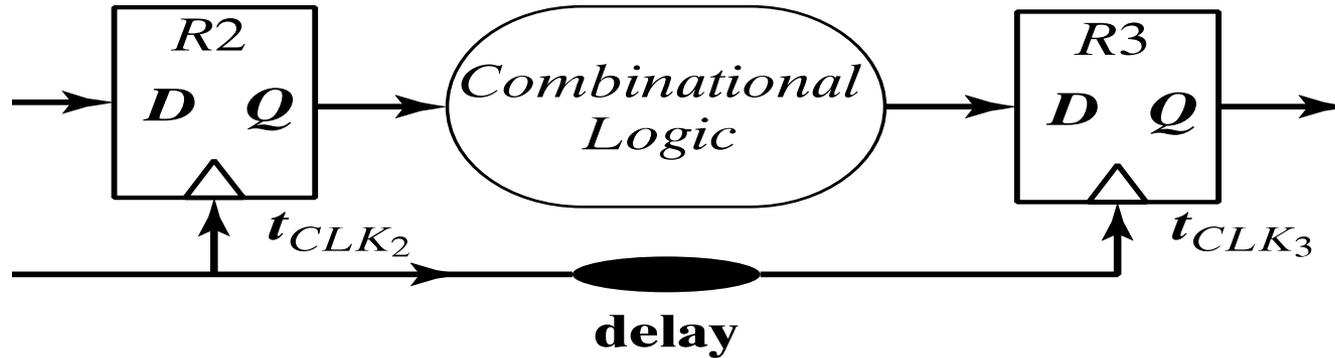
$t_{clk-q,max}$
 $t_{clk-q,min}$
 t_{setup}, t_{hold}

$t_{logic,max}$
 $t_{logic,min}$

Minimum cycle time:

$$T_{clk} + \delta = t_{clk-q,max} + t_{setup} + t_{logic,max}$$

Timing Constraints



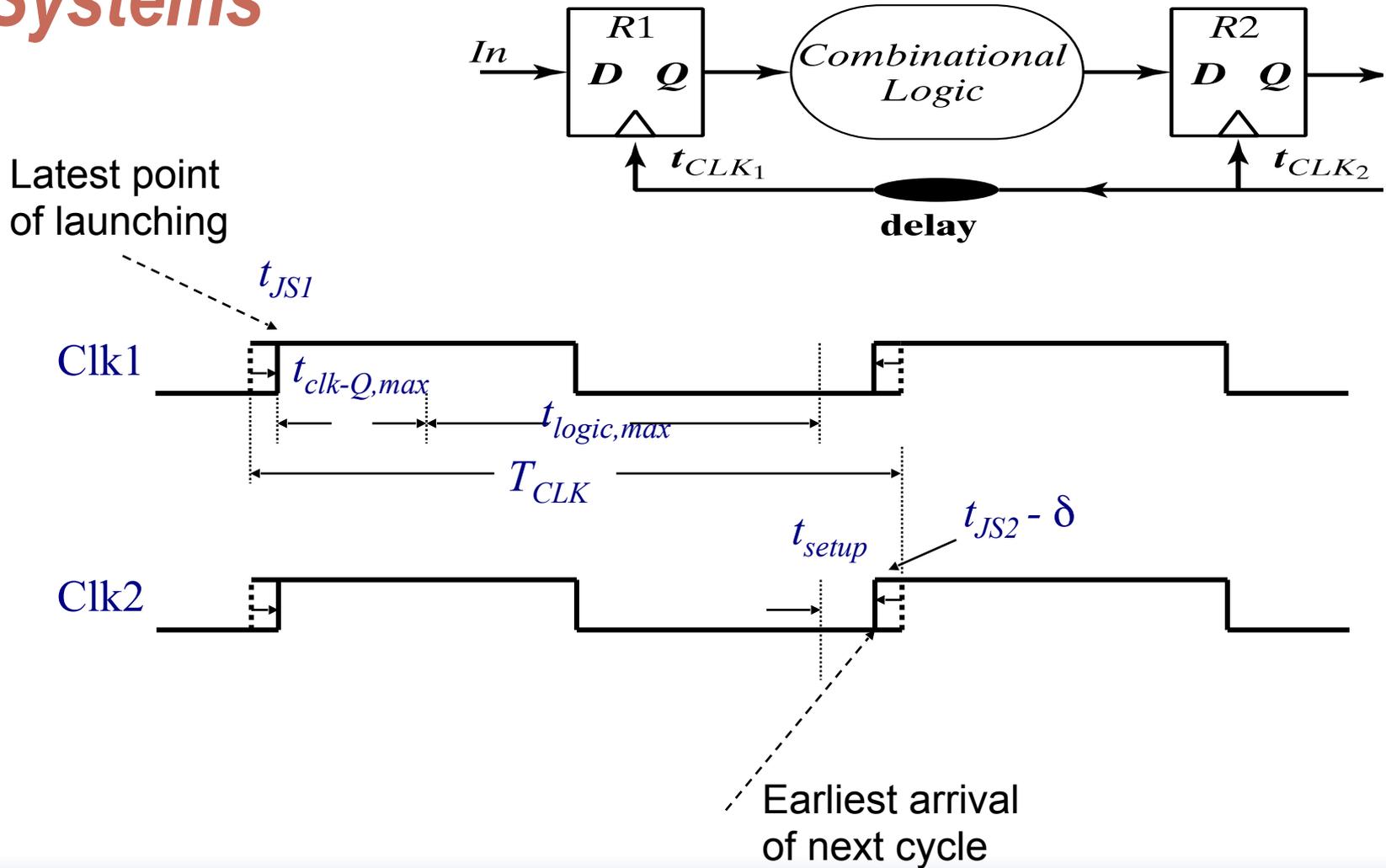
$t_{clk-q,max}$
 $t_{clk-q,min}$
 t_{setup}, t_{hold}

$t_{logic,max}$
 $t_{logic,min}$

Hold time constraint:

$$t_{(clk-q,min)} + t_{(logic,min)} > t_{hold} + \delta$$

Longest Logic Path in Edge-Triggered Systems



Clock Constraints in Edge-Triggered Systems

If launching edge is late and receiving edge is early, the data will not be too late if:

$$t_{clk-q,max} + t_{logic,max} + t_{setup} < T_{CLK} - t_{JS,1} - t_{JS,2} + \delta$$

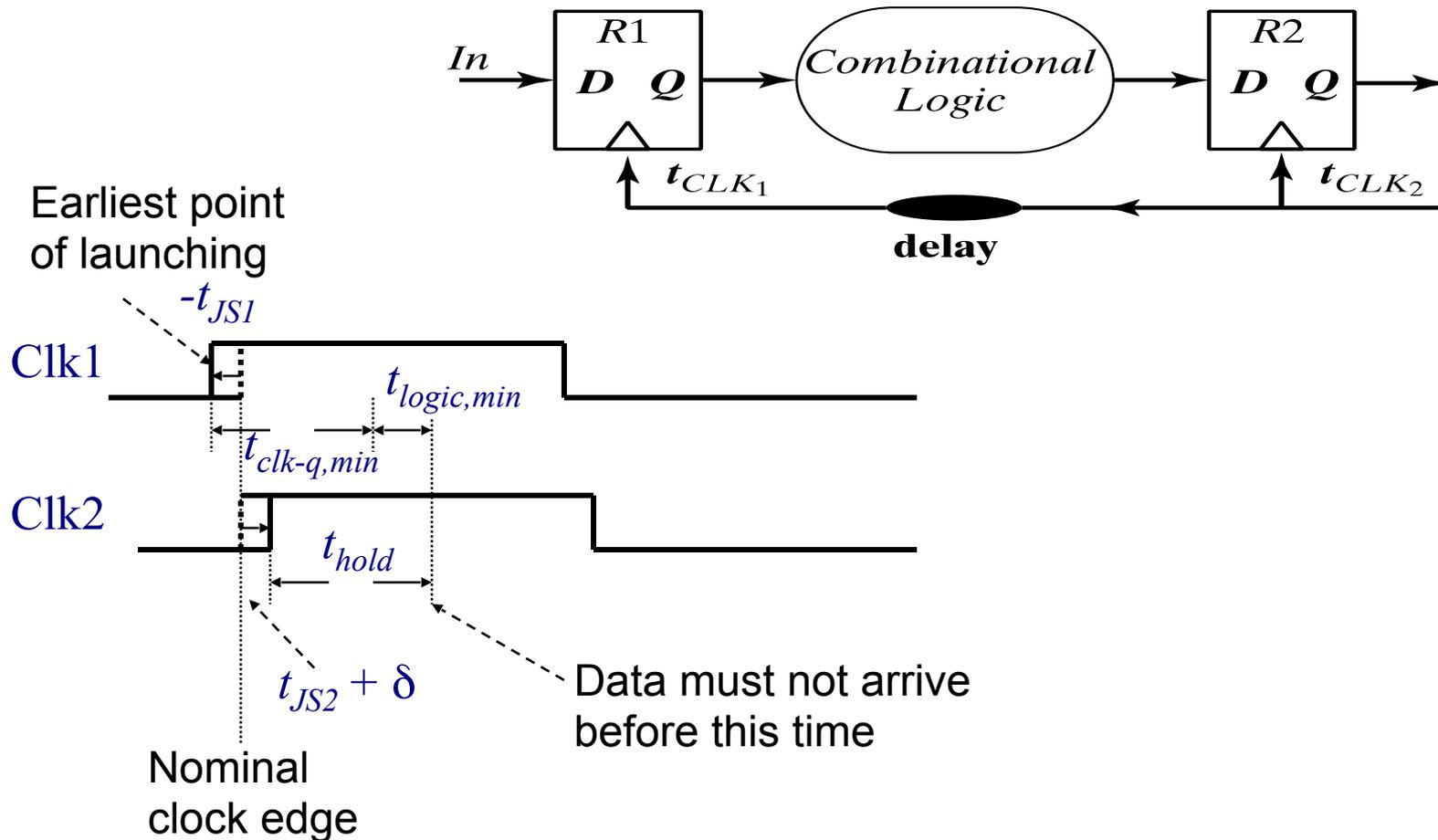
Minimum cycle time is determined by the maximum delays through the logic

$$t_{clk-q,max} + t_{logic,max} + t_{setup} - \delta + 2t_{JS} < T_{CLK}$$

Skew can be either positive or negative

Jitter t_{JS} usually expressed as peak-to-peak or N x rms value

Shortest Path



Clock Constraints in Edge-Triggered Systems

If launching edge is early and receiving edge is late:

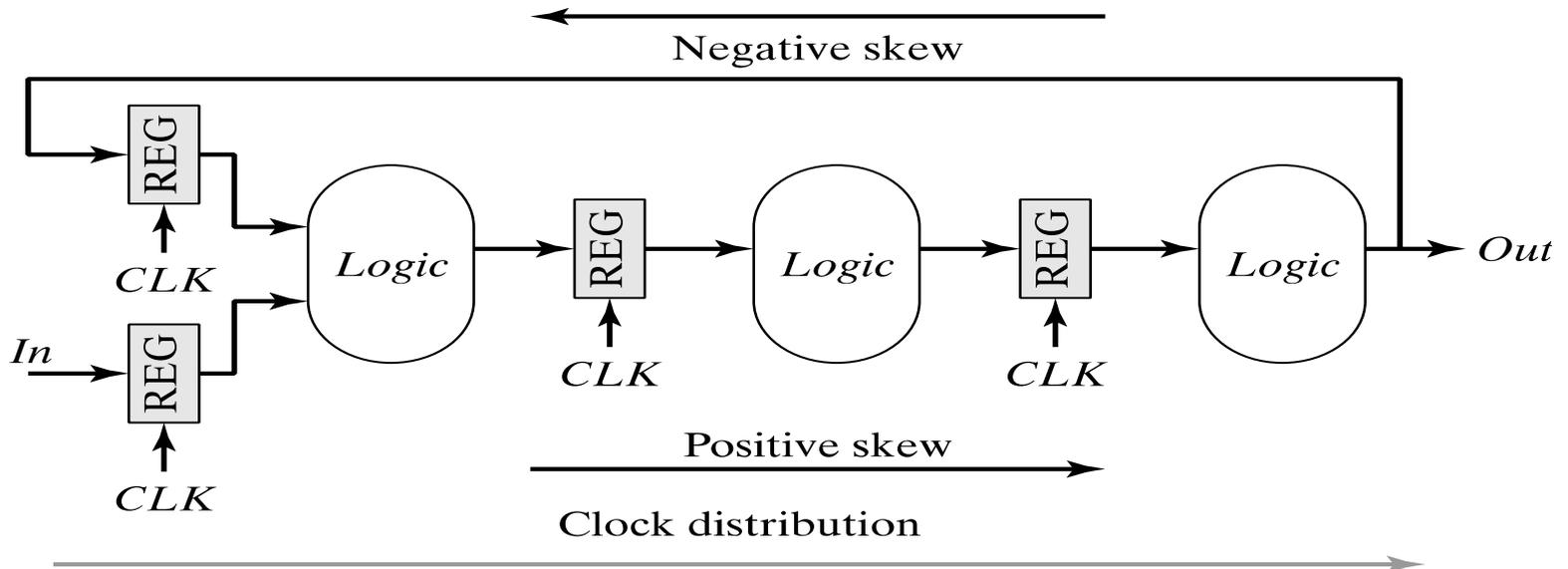
$$t_{clk-q,min} + t_{logic,min} - t_{JS,1} > t_{hold} + t_{JS,2} + \delta$$

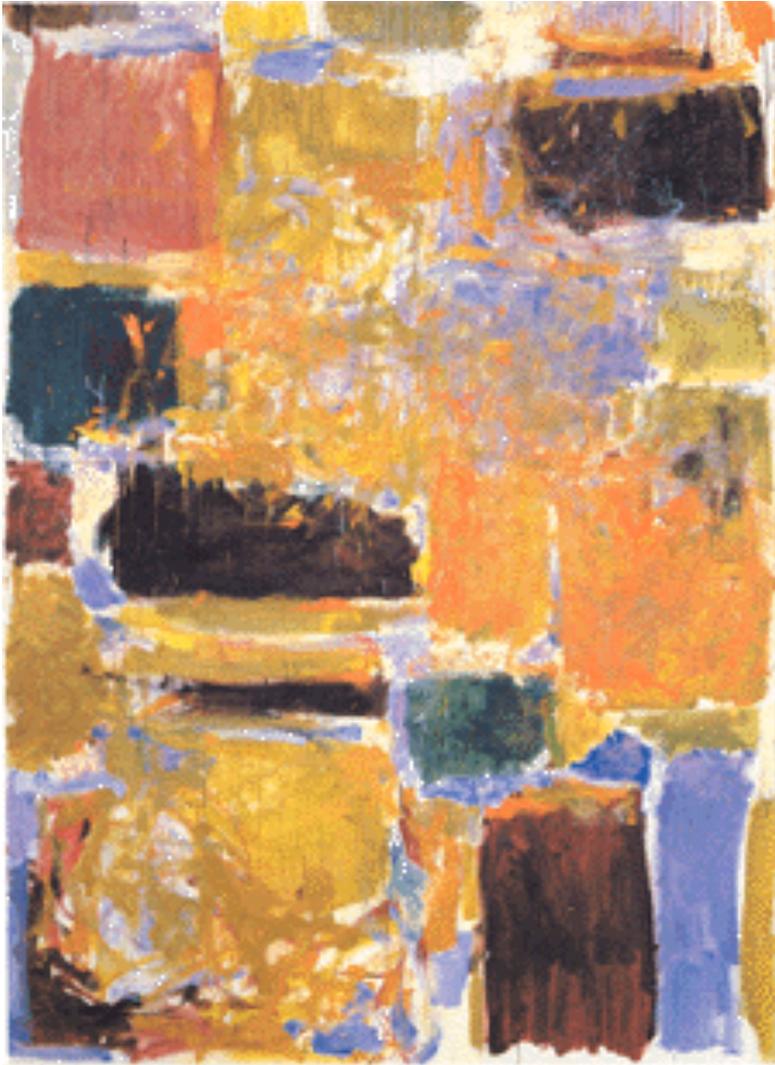
Minimum logic delay

$$t_{clk-q,min} + t_{logic,min} > t_{hold} + 2t_{JS} + \delta$$

(This assumes jitter at launching and receiving clocks are independent – which usually is not true)

Datapath with Feedback





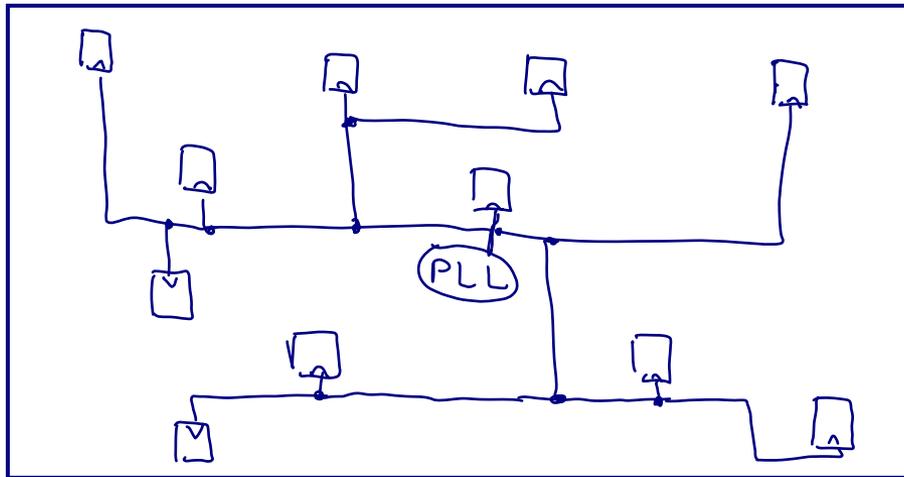
Clock Distribution

Clock Distribution

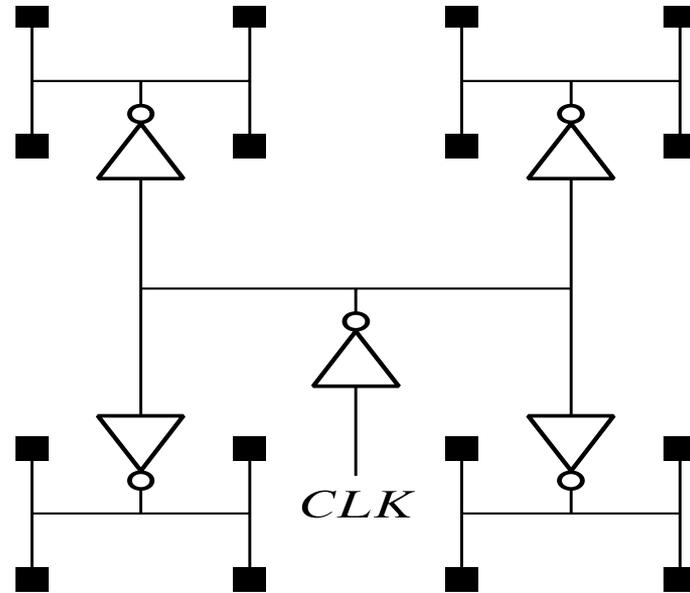
- Single clock generally used to synchronize all logic on the same chip (or region of chip)
 - Need to distribute clock over the entire region
 - While maintaining low skew/jitter
 - (And without burning too much power)

Clock Distribution

- ❑ What's wrong with just routing wires to every point that needs a clock?

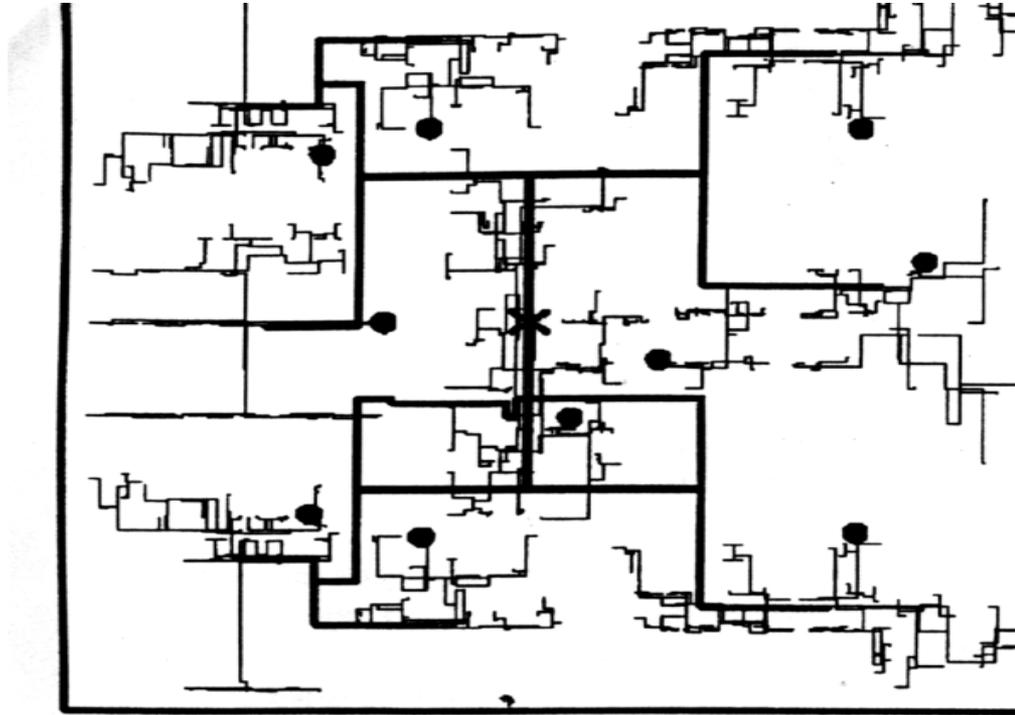


H-Tree



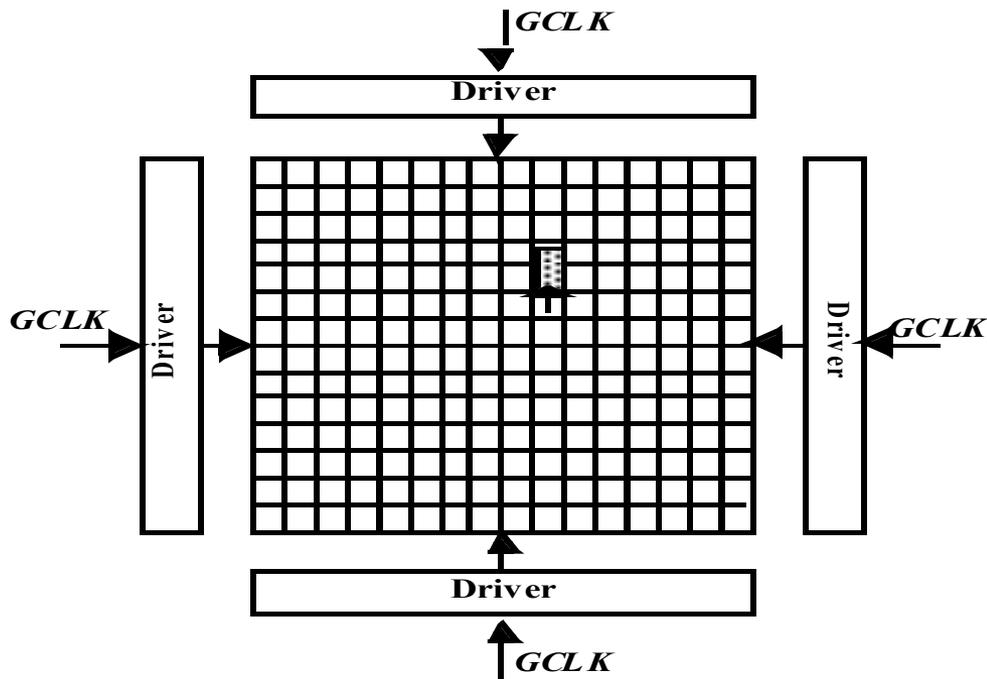
Equal wire length/number of buffers to get to every location

More realistic H-tree



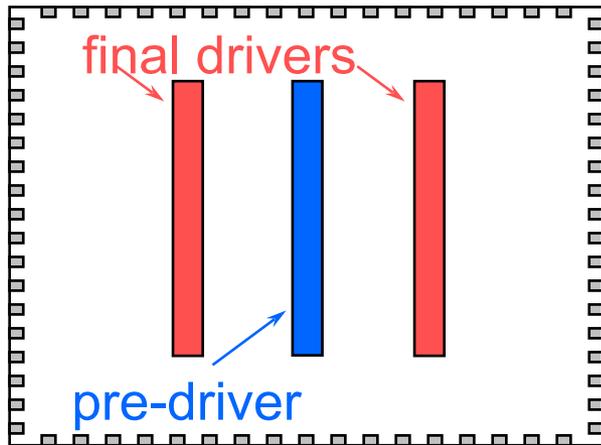
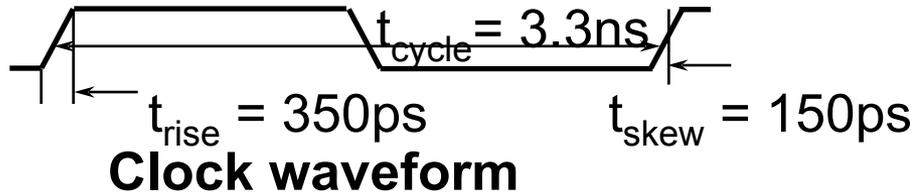
[Restle98]

Clock Grid



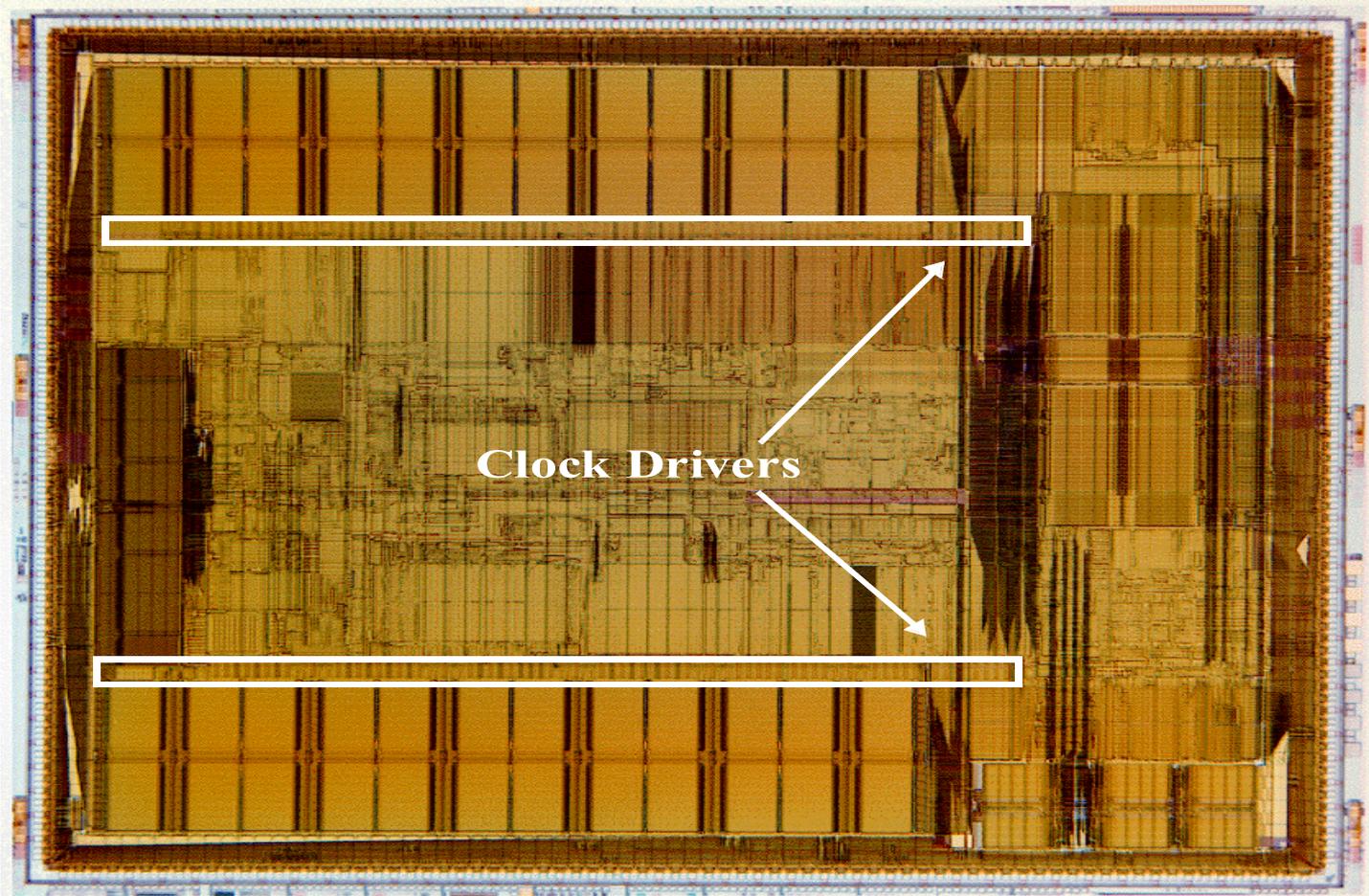
- No RC matching
- But huge power

Example: DEC Alpha 21164 (1995)



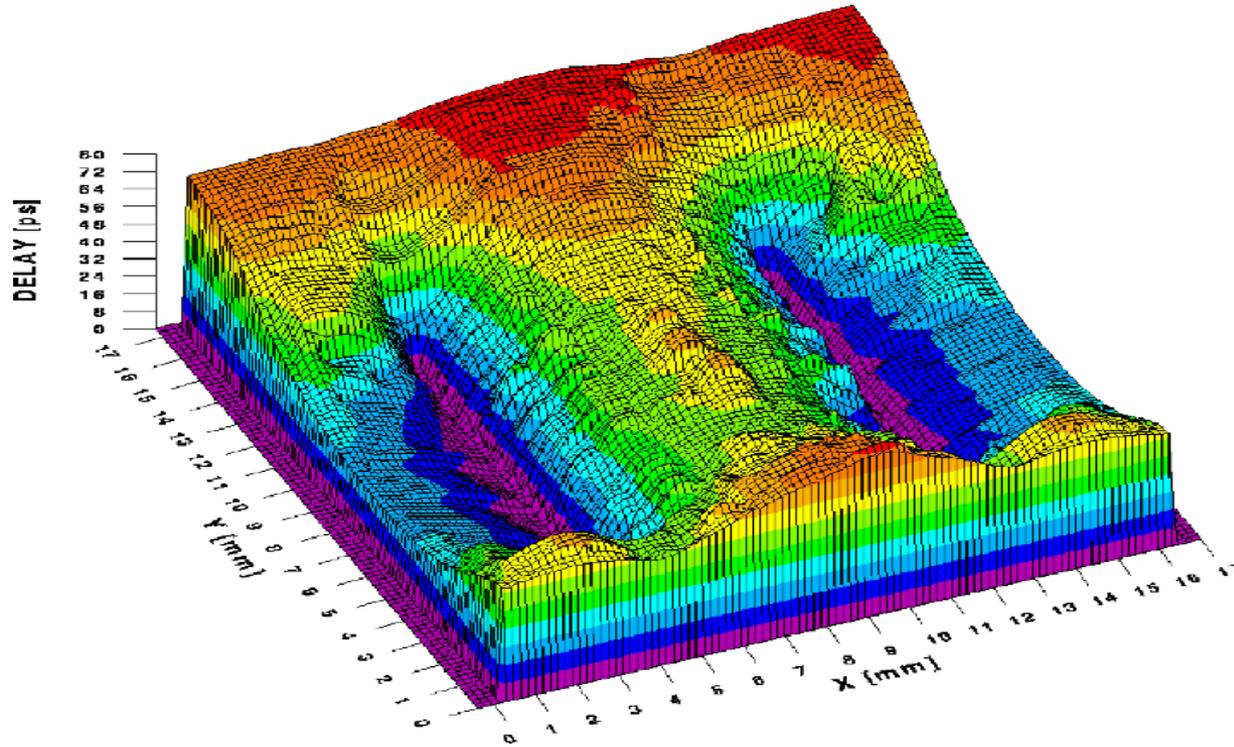
Location of clock driver on die

- ❑ 2 phase single wire clock, distributed globally
- ❑ 2 distributed driver channels
 - Reduced RC delay/skew
 - Improved thermal distribution
 - 3.75nF clock load, 20W power
 - 58 cm final driver width
- ❑ Local inverters for latching
- ❑ Conditional clocks in caches to reduce power



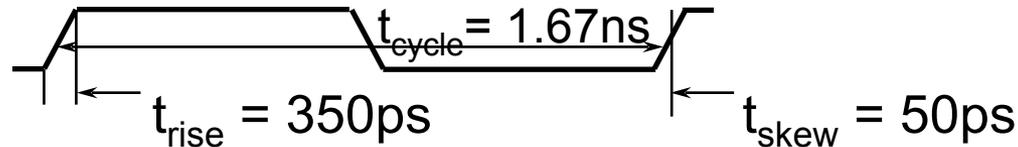
Clock Drivers

Clock Skew in Alpha Processor

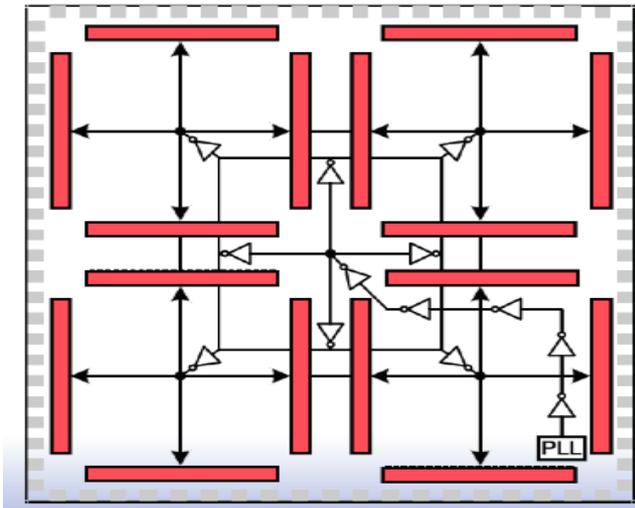


EV6 (Alpha 21264) Clocking

600 MHz – 0.35 micron CMOS

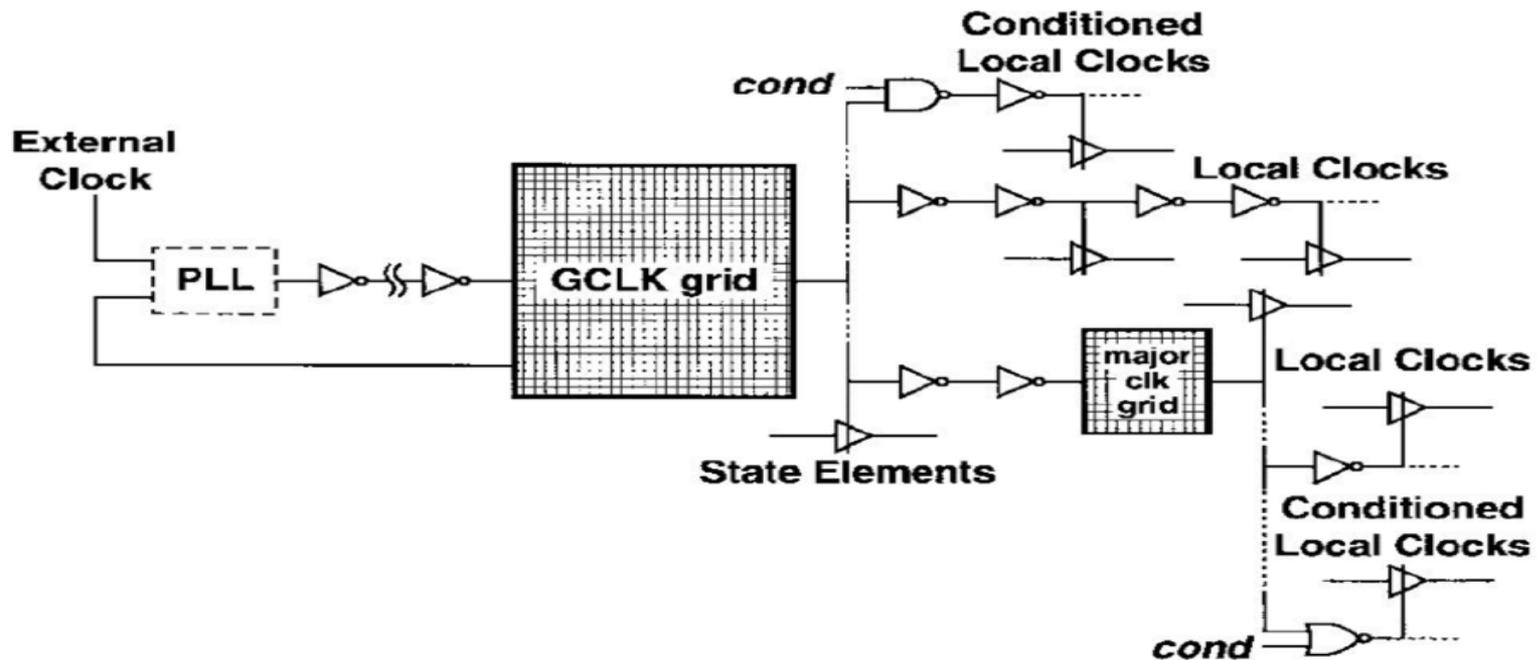


Global clock waveform

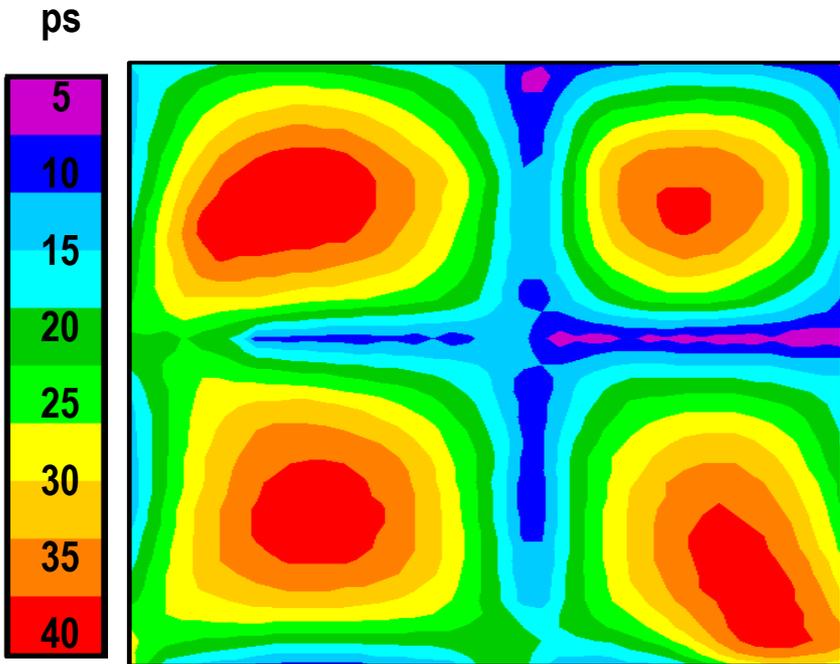


- ❑ 2 Phase, with multiple conditional buffered clocks
 - 2.8 nF clock load
 - 40 cm final driver width
- ❑ Local clocks can be gated “off” to save power
- ❑ Reduced load/skew
- ❑ Reduced thermal issues
- ❑ Multiple clocks complicate race checking

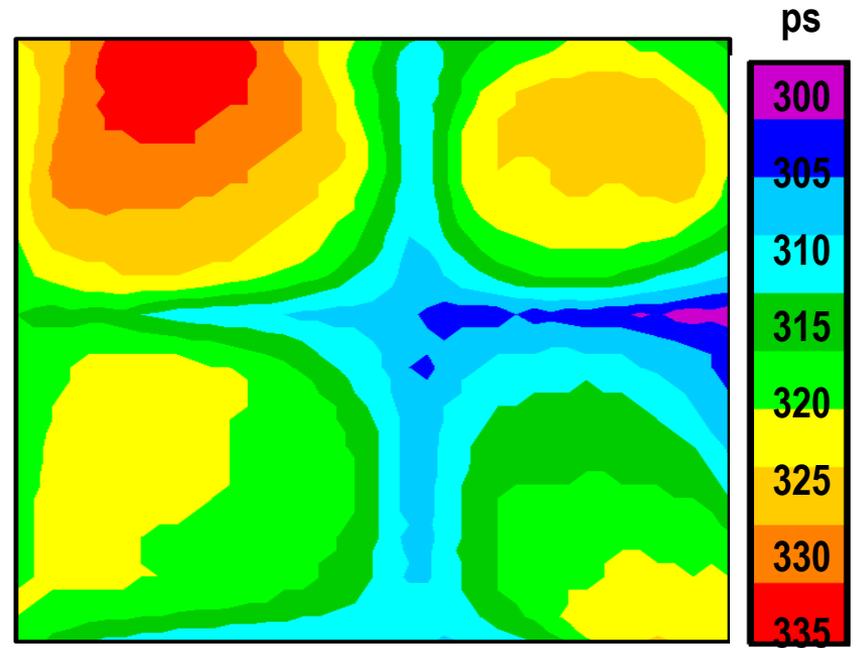
21264 Clocking



EV6 Clock Results



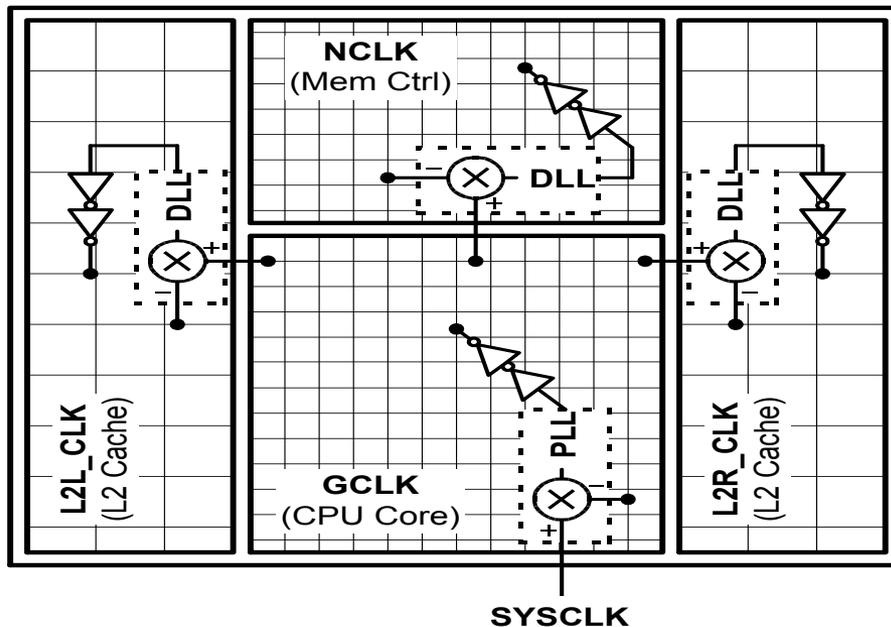
GCLK Skew
(at Vdd/2 Crossings)



GCLK Rise Times
(20% to 80% Extrapolated to 0% to 100%)

EV7 Clock Hierarchy (2002)

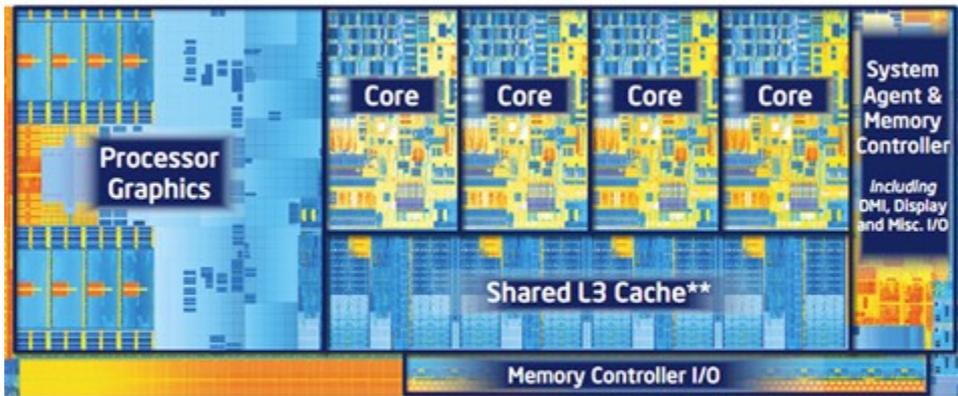
Active Skew Management and Multiple Clock Domains



- + widely dispersed drivers
- + DLLs compensate static and low-frequency variation
- + divides design and verification effort
- DLL design and verification is added work
- + tailored clocks

Modern Processors

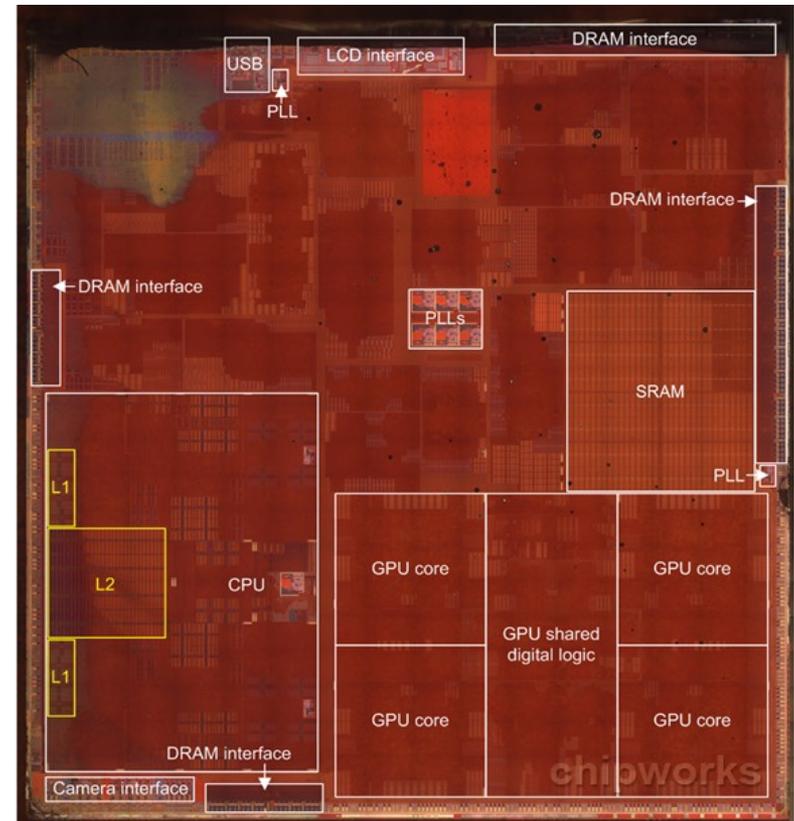
3rd Generation Intel® Core™ Processor: 22nm Process



New architecture with shared cache delivering more performance and energy efficiency

Quad Core die with Intel® HD Graphics 4000 shown above
Transistor count: 1.4Billion Die size: 160mm²
** Cache is shared across all 4 cores and processor graphics

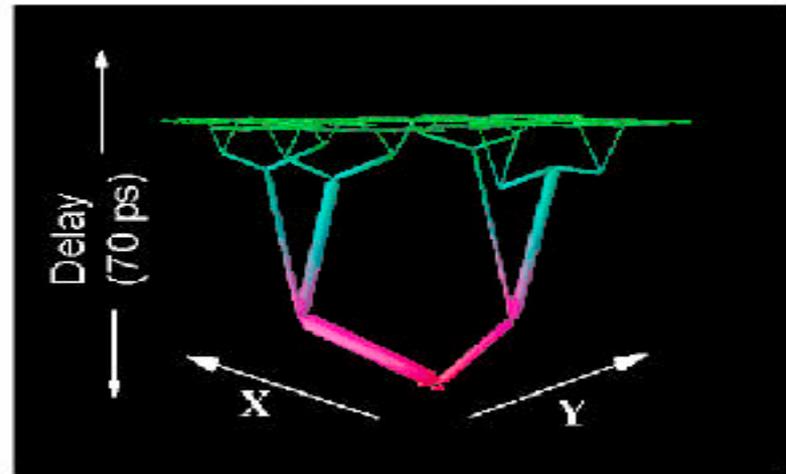
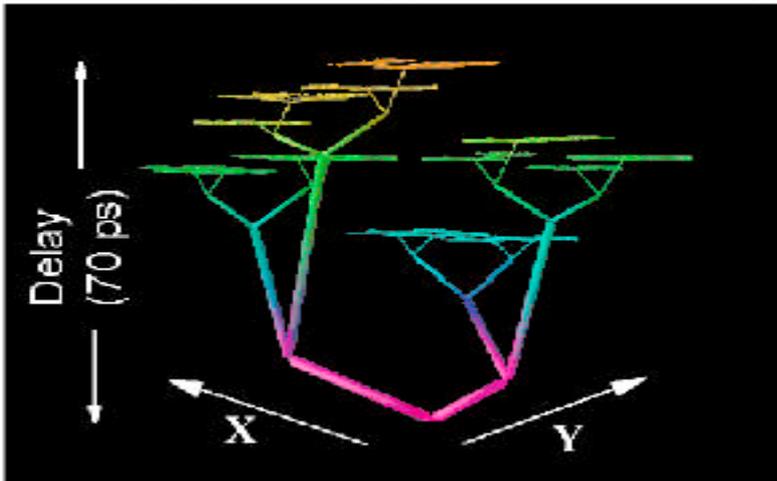
Apple A7



Clock Animations

- By Phillip Restle (IBM)

<http://www.research.ibm.com/people/r/restle/resonate.html>

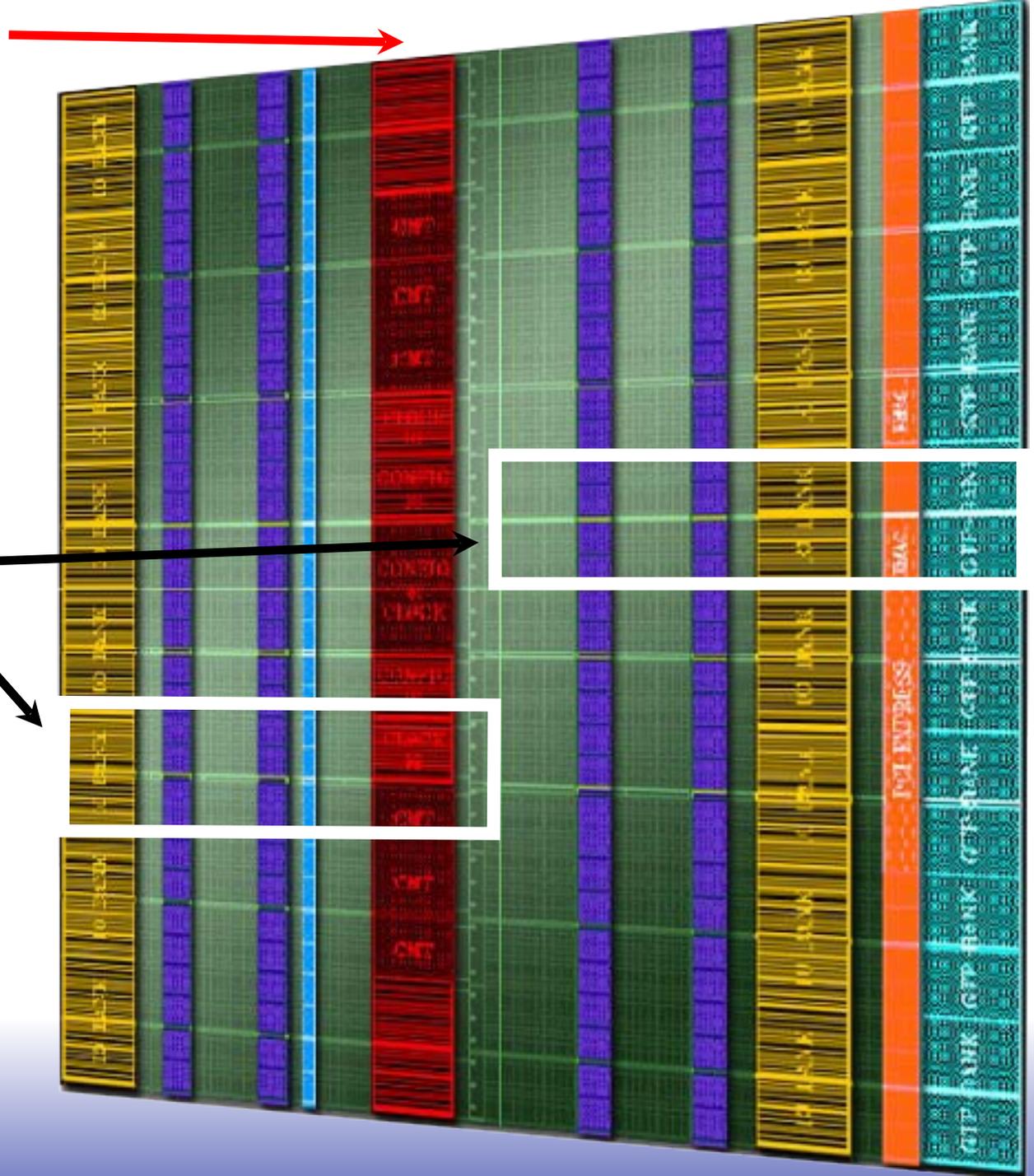


Clock circuits live in center column.

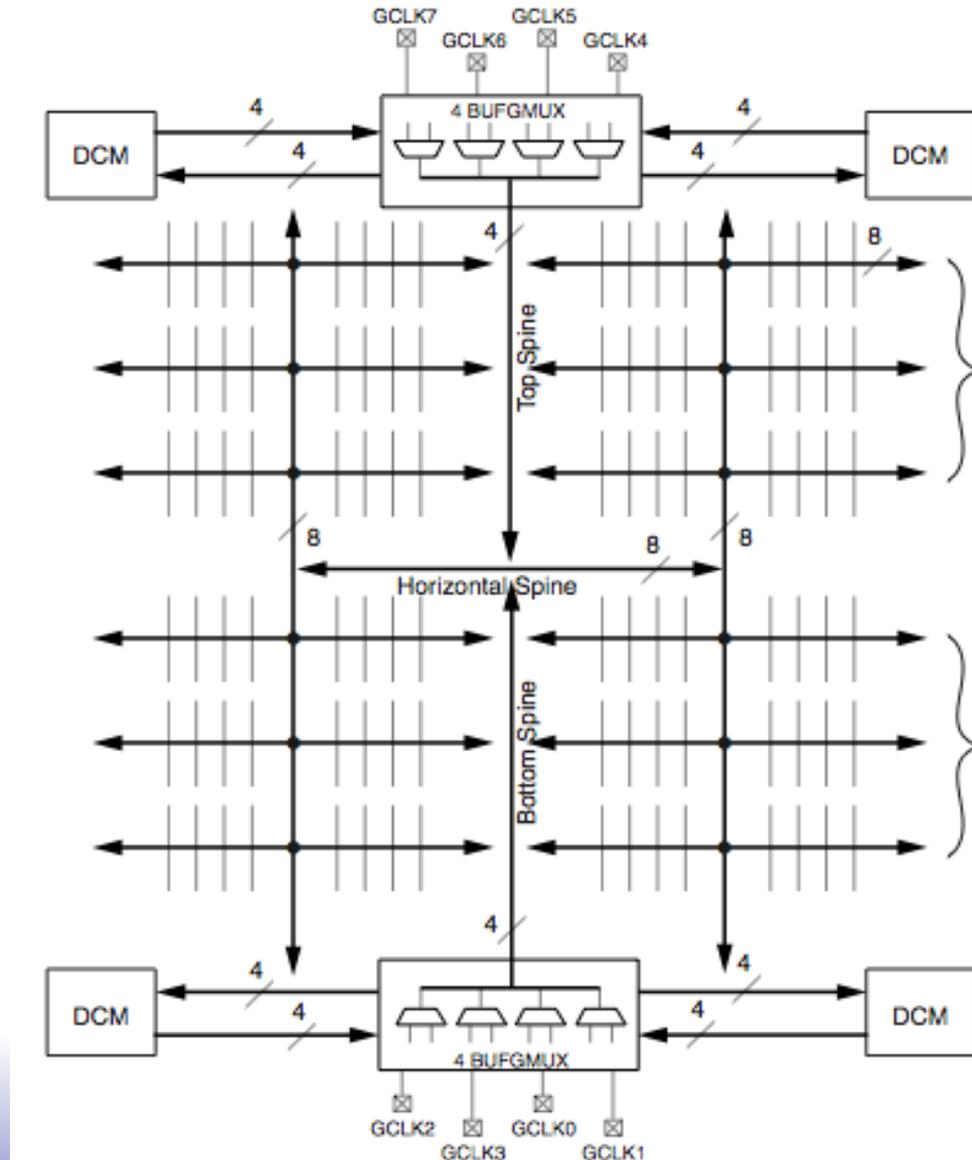
32 global clock wires go down the red column.

Any 10 may be sent to a clock region.

Also, 4 regional clocks (restricted functionality).

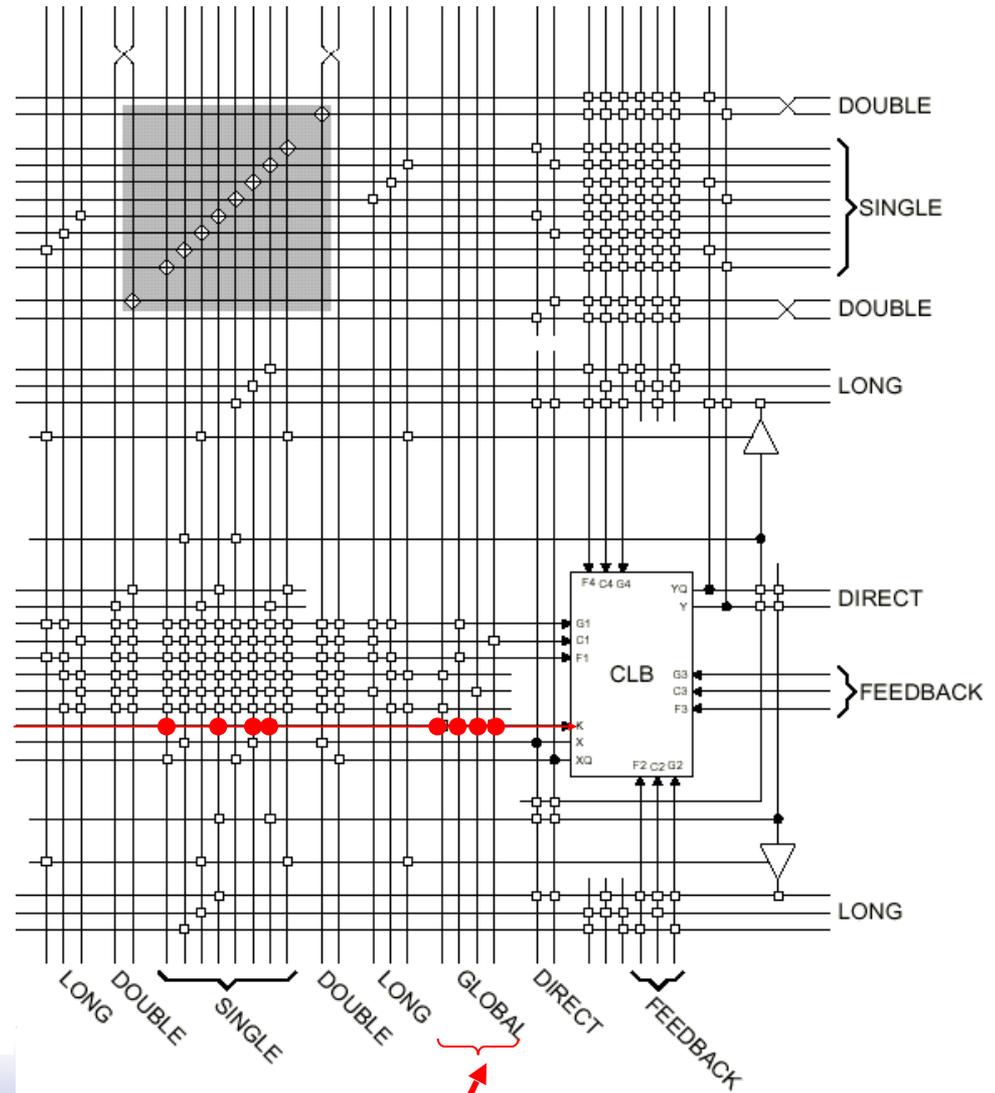
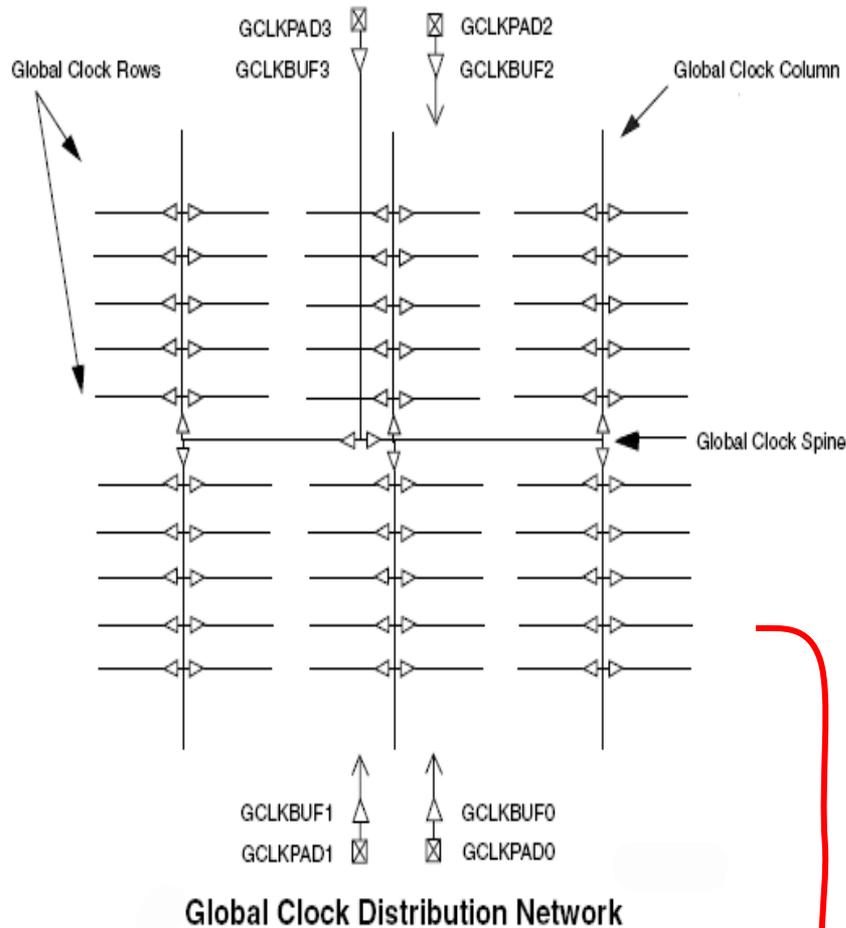


Clocks have dedicated wires (low skew)



From: Xilinx Spartan 3 data sheet. Virtex is similar.

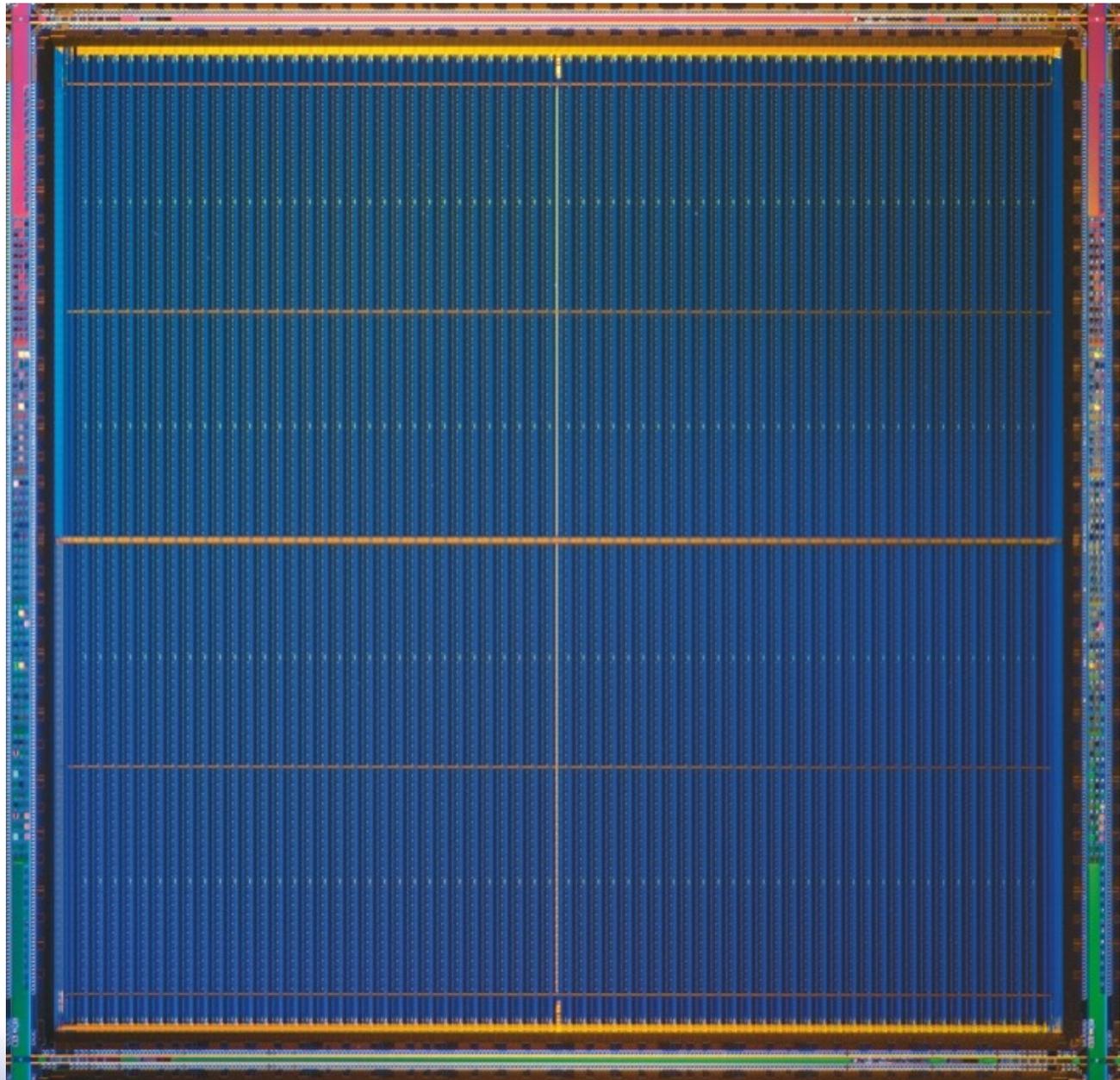
Low-skew Clocking in FPGAs

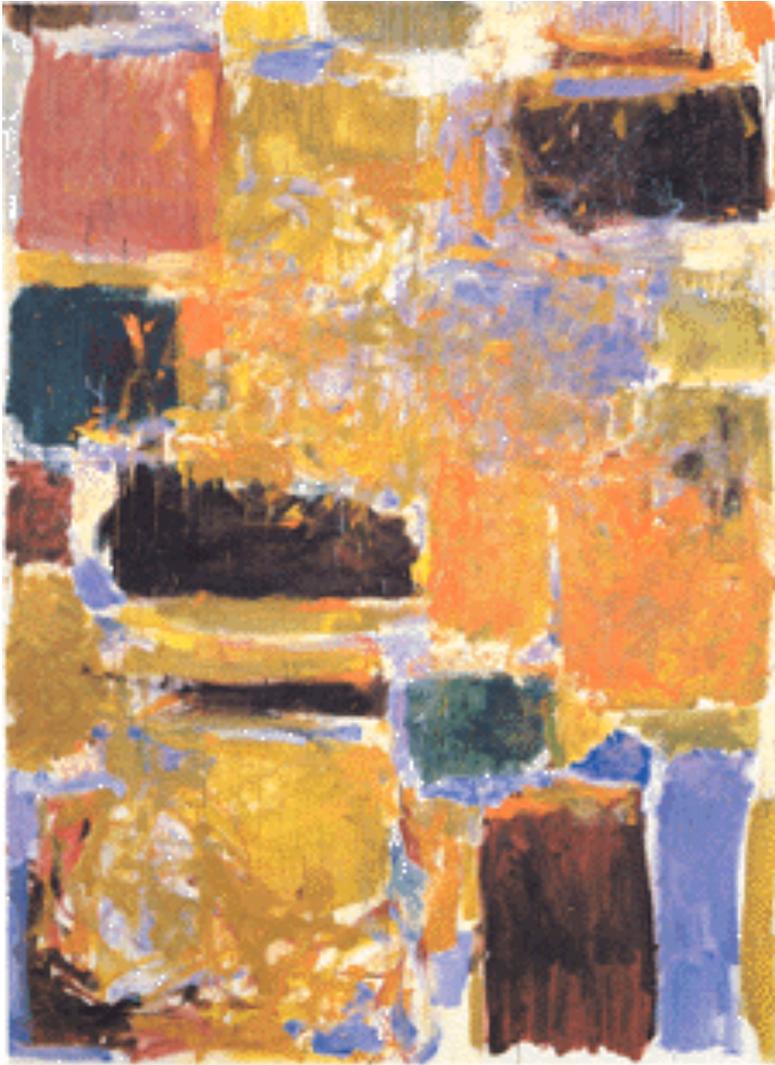


Figures from Xilinx App Notes

***Die
photo:
Xilinx
Virtex***

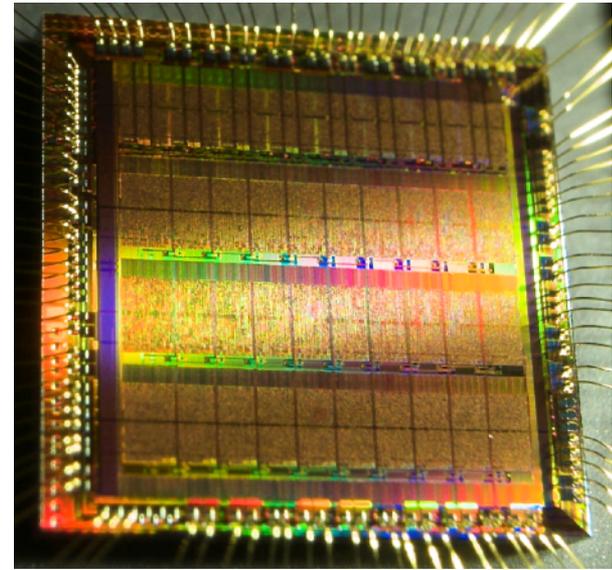
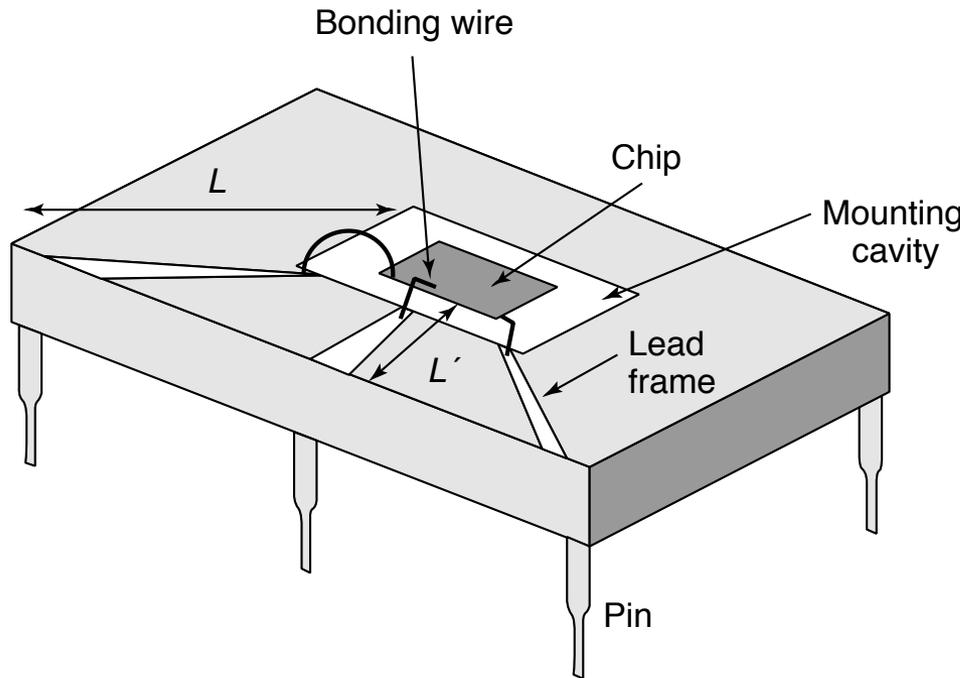
***Gold
wires
are the
clock
tree.***





Chip Packaging

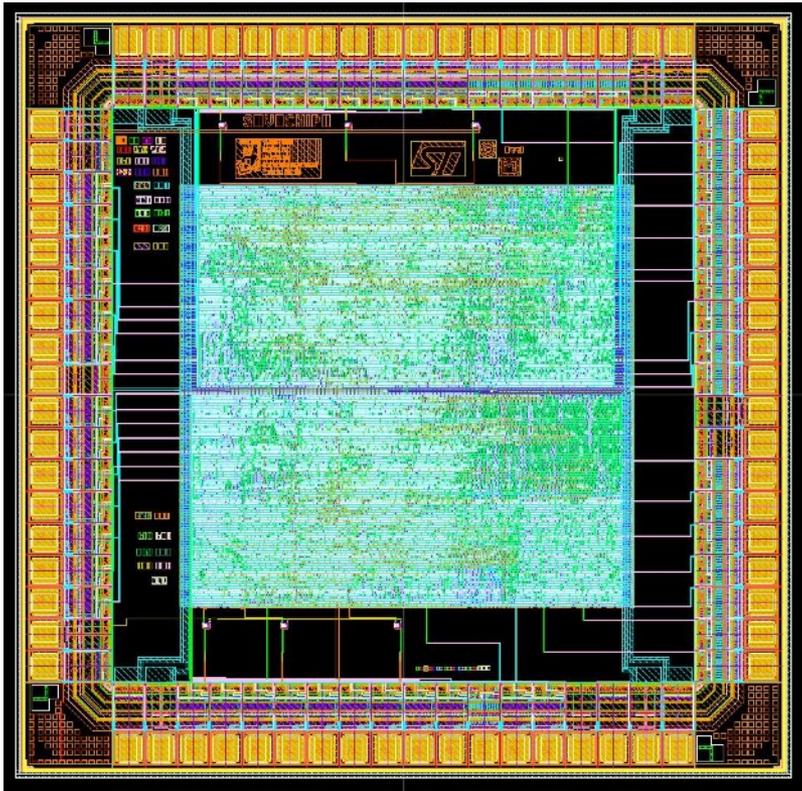
Chip Packaging



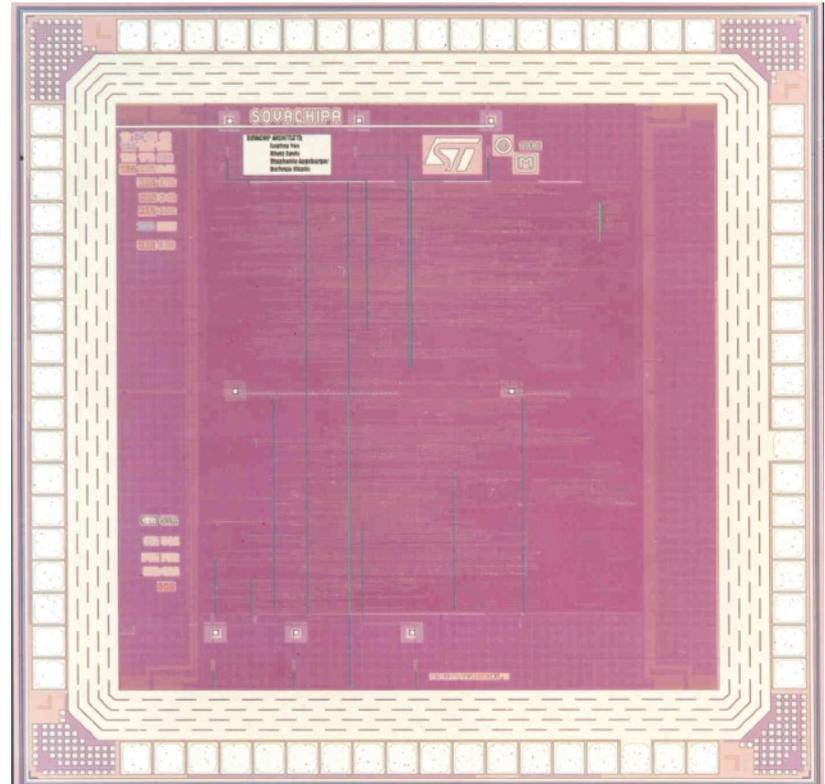
- Bond wires ($\sim 25\mu\text{m}$) are used to connect the package to the chip
- Pads are arranged in a frame around the chip
- Pads are relatively large ($\sim 100\mu\text{m}$ in $0.25\mu\text{m}$ technology), with large pitch ($100\mu\text{m}$)
- $60\mu\text{m} \times 80\mu\text{m}$ at $80\mu\text{m}$ pitch in 45nm
- Many chips are 'pad limited'

Pad Frame

Layout

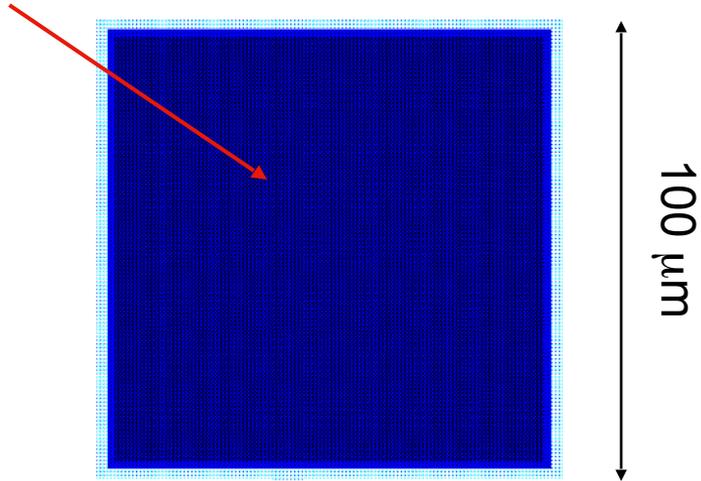


Die Photo

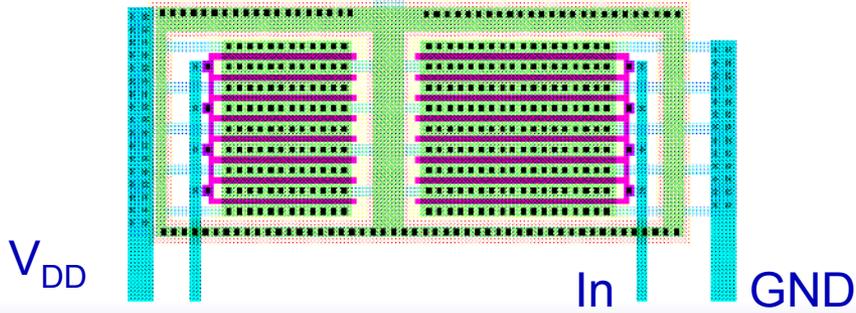


Bonding Pad Design

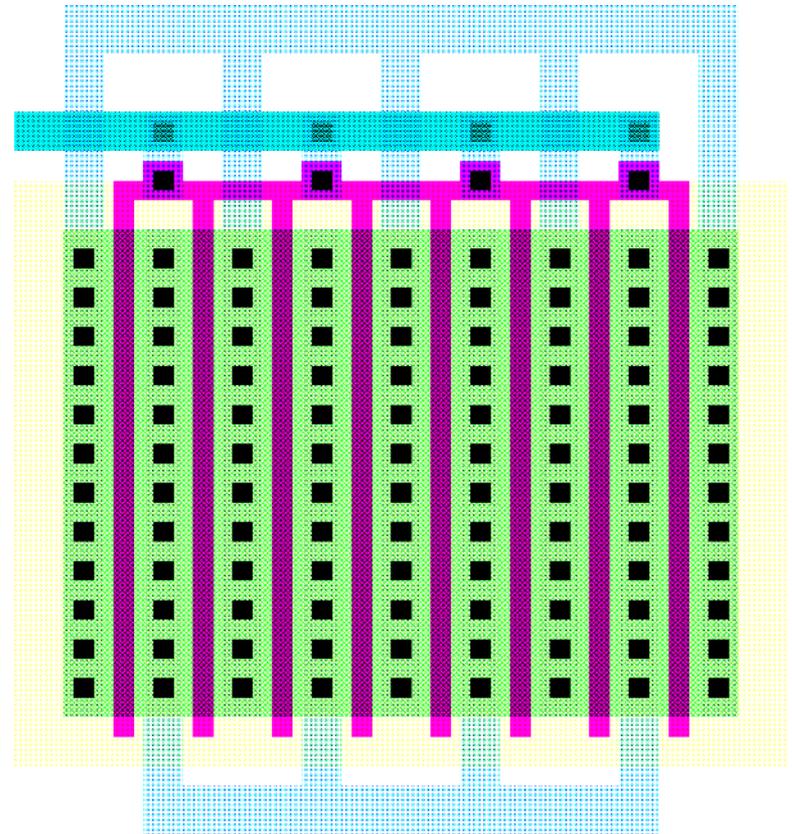
Bonding Pad



Out



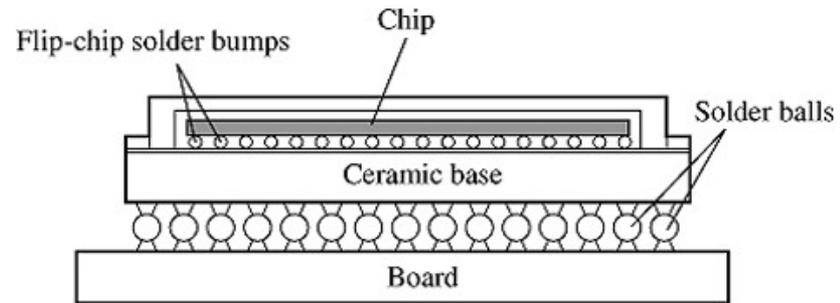
GND



Out

Chip Packaging

- An alternative is 'flip-chip':
 - Pads are distributed around the chip
 - The solder balls are placed on pads
 - The chip is 'flipped' onto the package
 - Pads still large
 - But can have many more of them



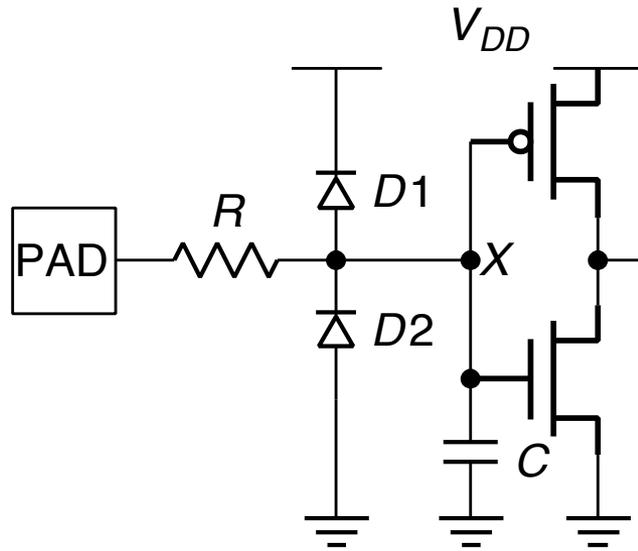
(b) Ball grid array packaging



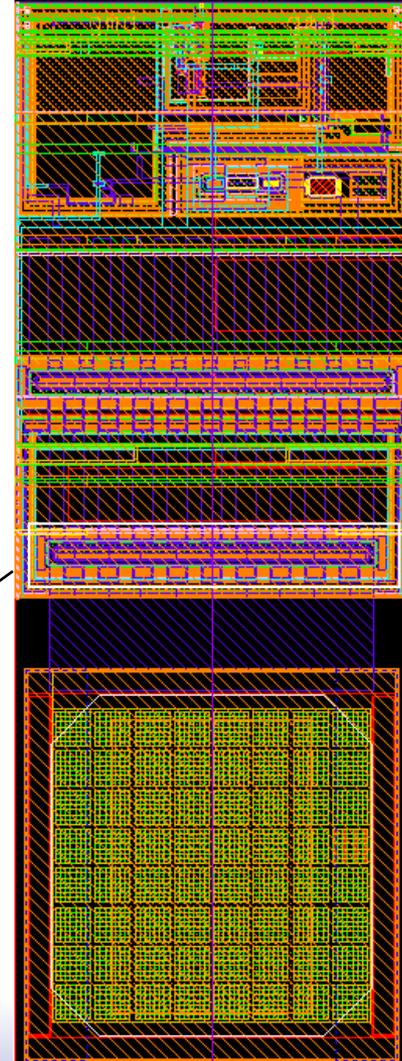
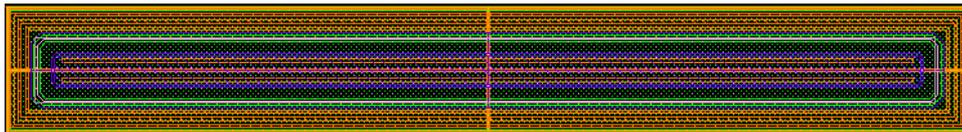
ESD Protection

- ❑ When a chip is connected to a board or otherwise handled, there is unknown (potentially large) static voltage difference (a few kV)
- ❑ Equalizing potentials requires (large) charge flow through the pads
- ❑ Diodes sink this charge into the substrate – need guard rings to pick it up.

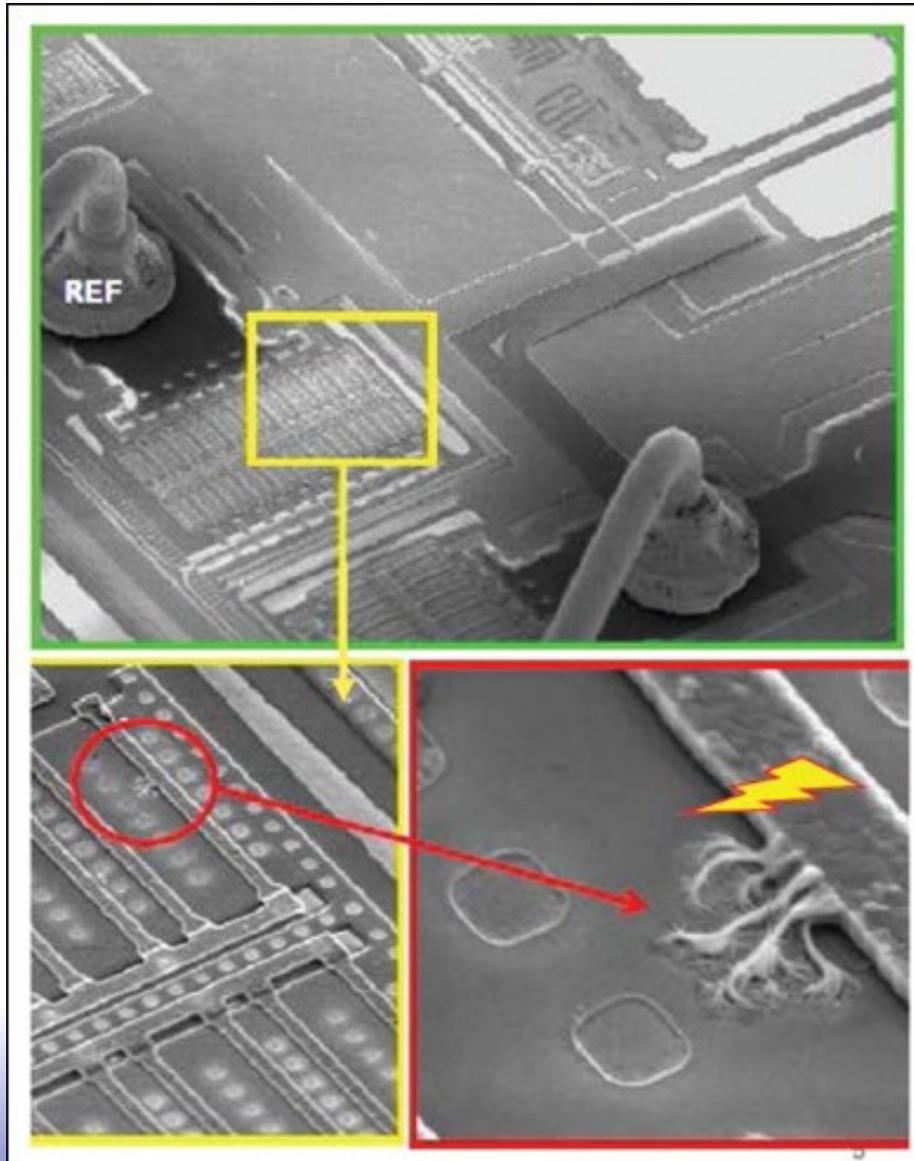
Pads + ESD Protection



Diode

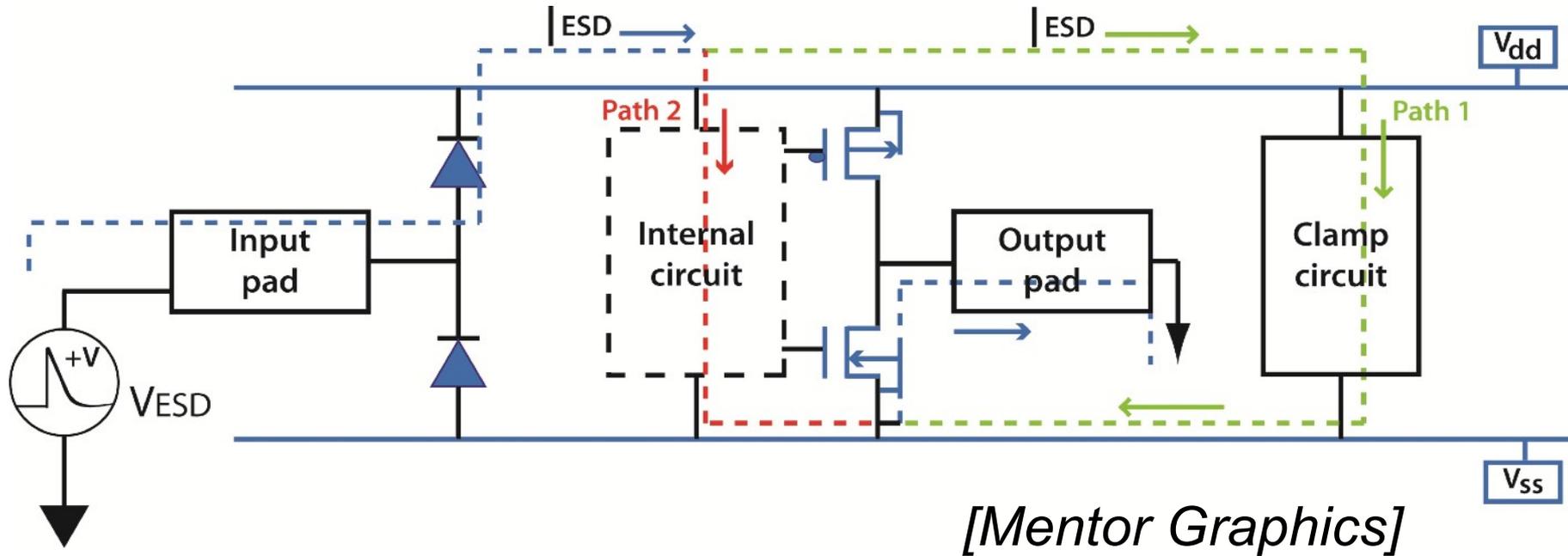


When Things Go Bad



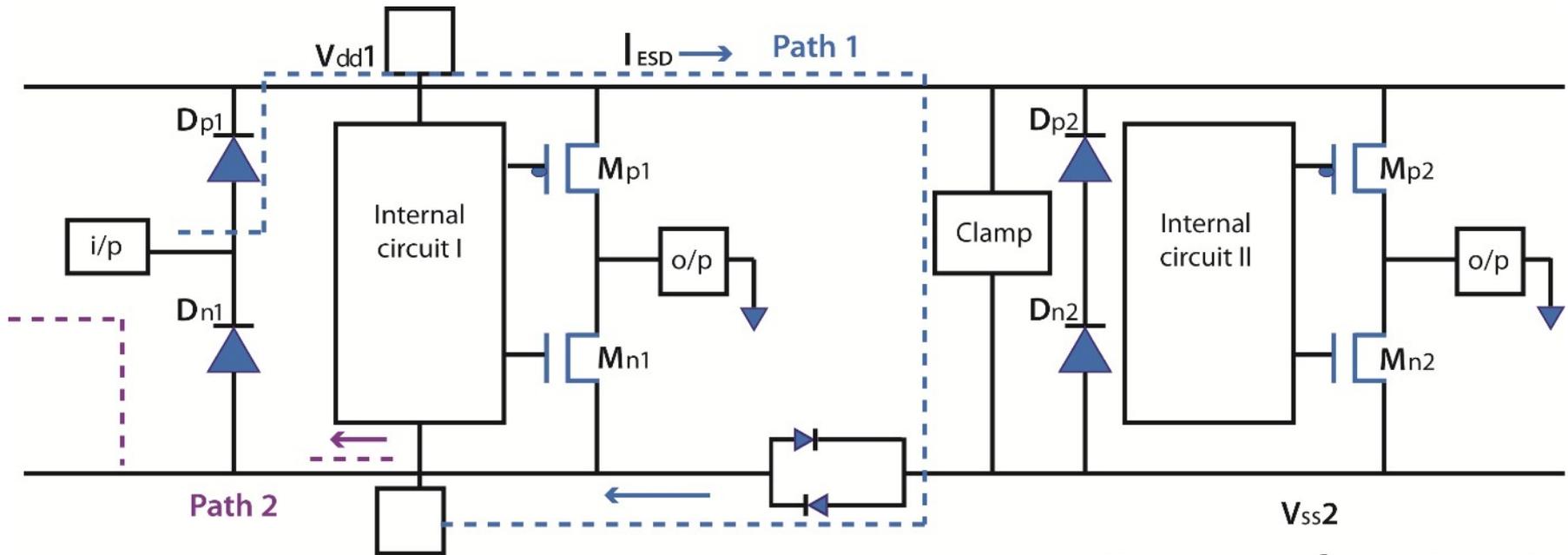
[Maxim]

Stray Paths



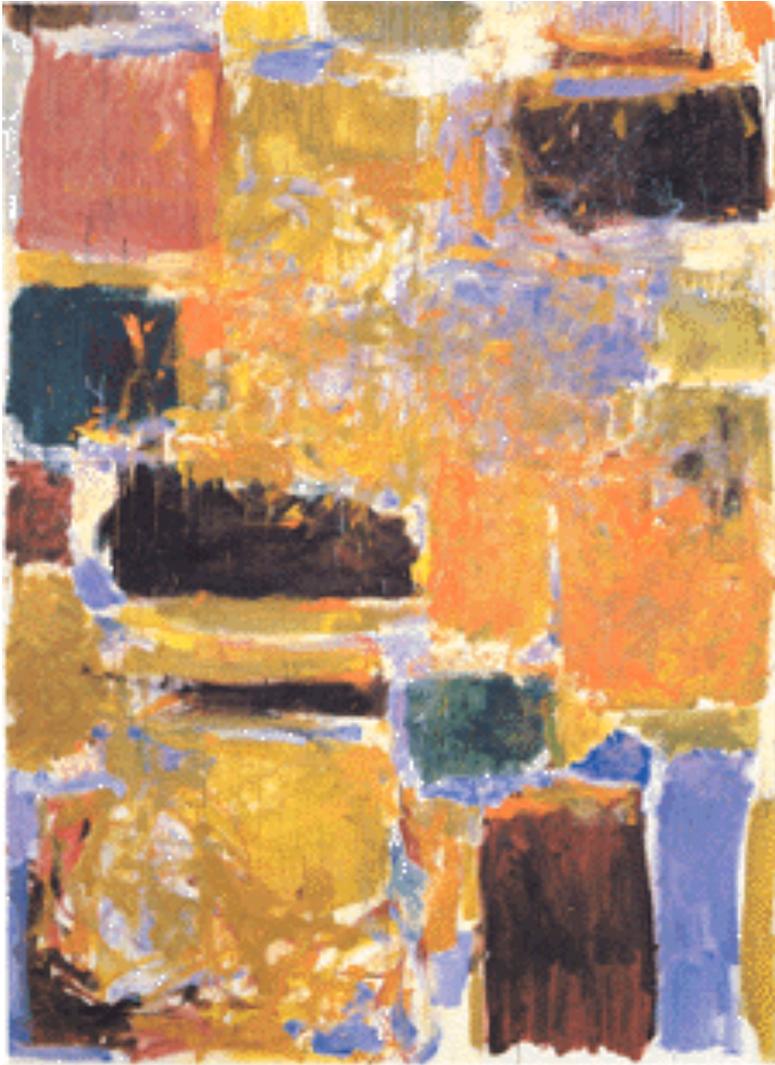
- Clamp circuit sinks the ESD current
 - Typically a few stacked diodes (2-4)

Split Ground Rails



[Mentor Graphics]

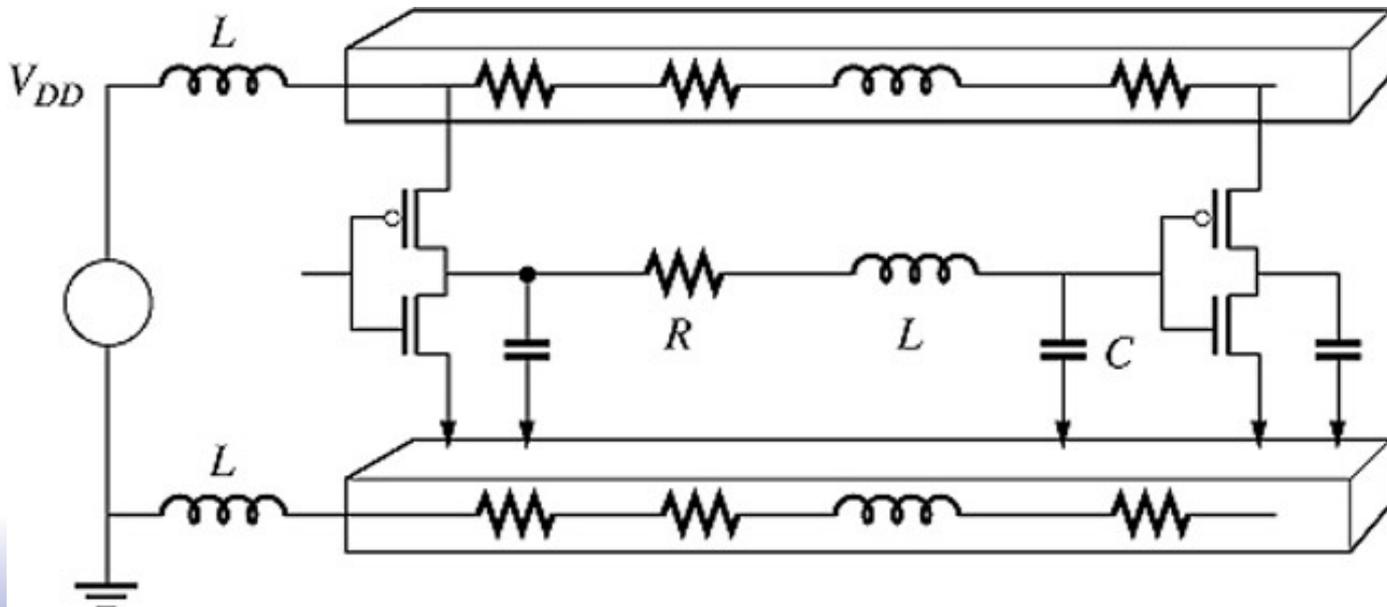
- Bidirectional diode fixes the ESD path



Power Distribution

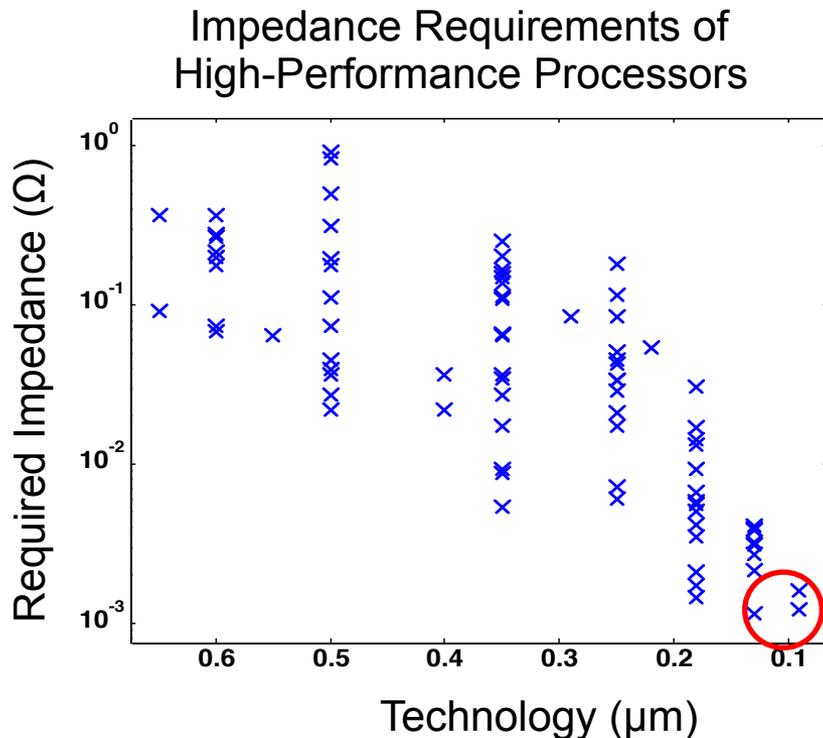
Power Supply Impedance

- ❑ No voltage source is ideal - $||Z|| > 0$
- ❑ Two principal elements increase Z :
 - Resistance of supply lines (IR drop)
 - Inductance of supply lines ($L \cdot di/dt$ drop)



Scaling and Supply Impedance

- Typical target for supply impedance is to get 5-10% variation of nominal supply (e.g., 100mV for 1V supply)



- In traditional scaling V_{dd} drops while power stays constant
- This forced drastic drop in supply impedance

- $V_{dd} \downarrow, I_{dd} \uparrow \rightarrow |Z_{required}| \downarrow \downarrow$

- Today's chips:

- $|Z_{required}| \approx 1 \text{ m}\Omega!$
- $V_{dd} = 1\text{V}, P=100\text{W} \Rightarrow I_{dd}=100\text{A}$
- For $\Delta V_{dd,max} = 100\text{mV}$,
 $Z_{dd,max} = 100\text{mV}/100\text{A} = 1\text{m}\Omega!$

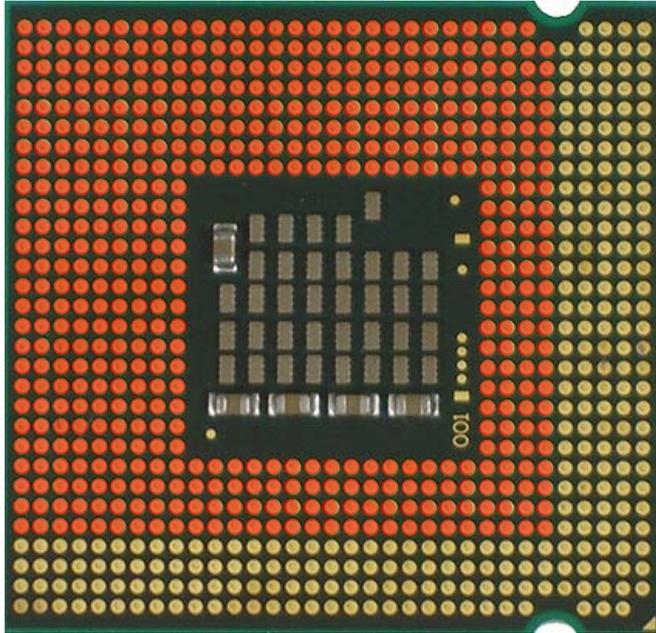
IR Drop Example

- Intel Pentium 4: ~103W at ~1.275V
 - $I_{dd} = 81\text{Amps}$

- For 10% IR drop, total distribution resistance must be less than **1.6mΩ**

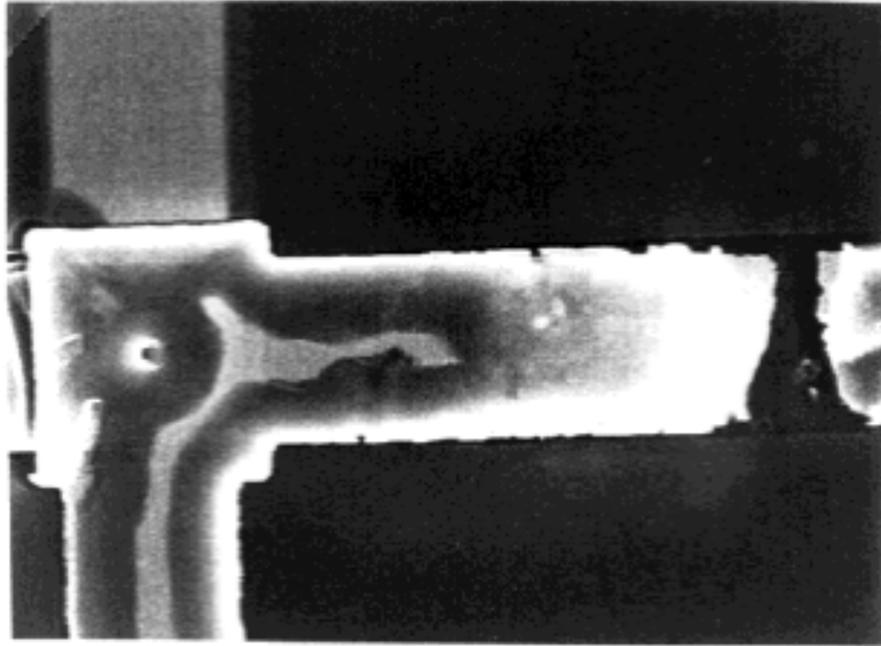
- On-chip wire $R \approx 20\text{m}\Omega/\text{sq.}$ (thick metal)
 - Can't meet R requirement even with multiple, complete layers dedicated to power
 - Main motivation for flip-chip packaging

Power Delivery



- ❑ Achieving such low impedance requires a lot of resources:
 - ~70% of package pins just for power
 - Top 2-3 (thick) metal layers

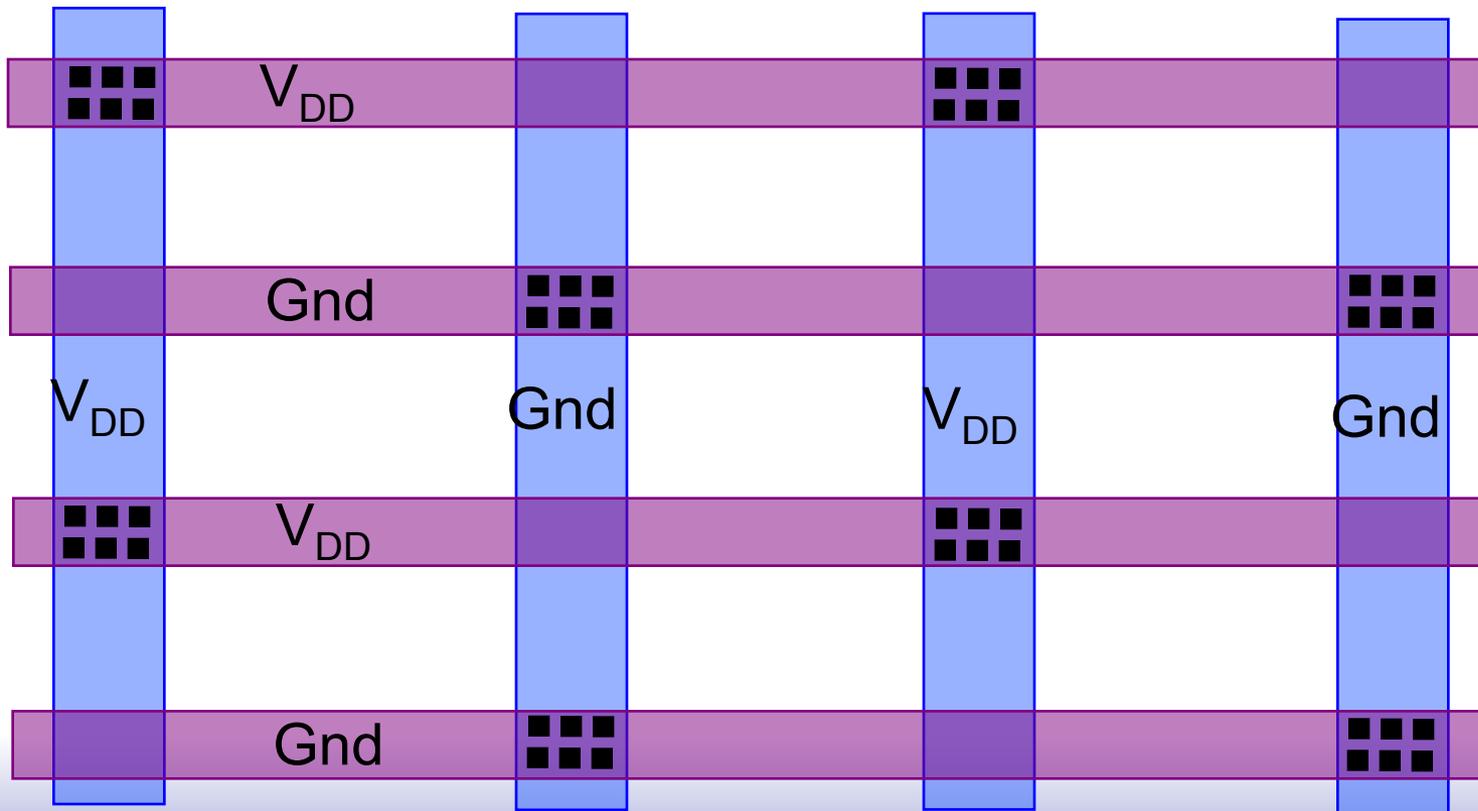
Not Just Impedance - Electromigration



- ❑ On-chip wires: current limited to $\sim 1\text{mA}/\mu\text{m}$ for 5-7 year lifetime

On-Chip Power Distribution

- ❑ Power network usually follows pre-defined template (often referred to as “power grid”)



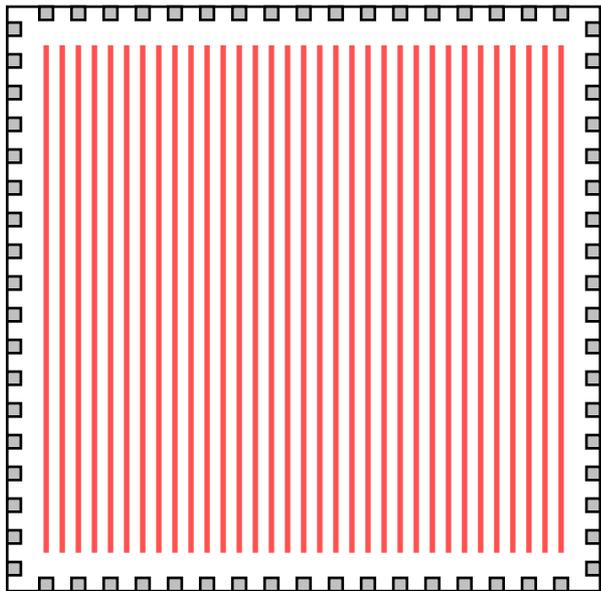
3 Metal Layer Approach (EV4)

3rd “coarse and thick” metal layer added to the technology for EV4 design

Power supplied from two sides of the die via 3rd metal layer

2nd metal layer used to form power grid

90% of 3rd metal layer used for power/clock routing



Metal 3



Metal 2



Metal 1

Courtesy Compaq

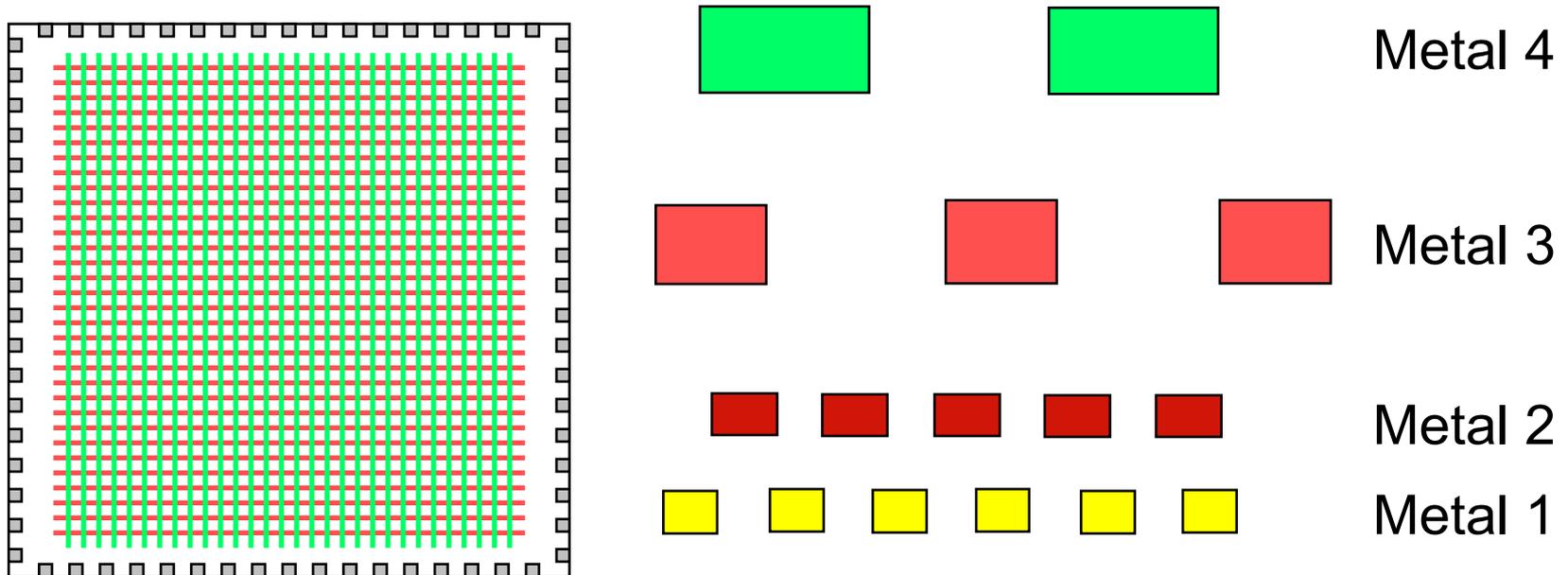
4 Metal Layers Approach (EV5)

4th “coarse and thick” metal layer added to the technology for EV5 design

Power supplied from four sides of the die

Grid strapping done all in coarse metal

90% of 3rd and 4th metals used for power/clock routing



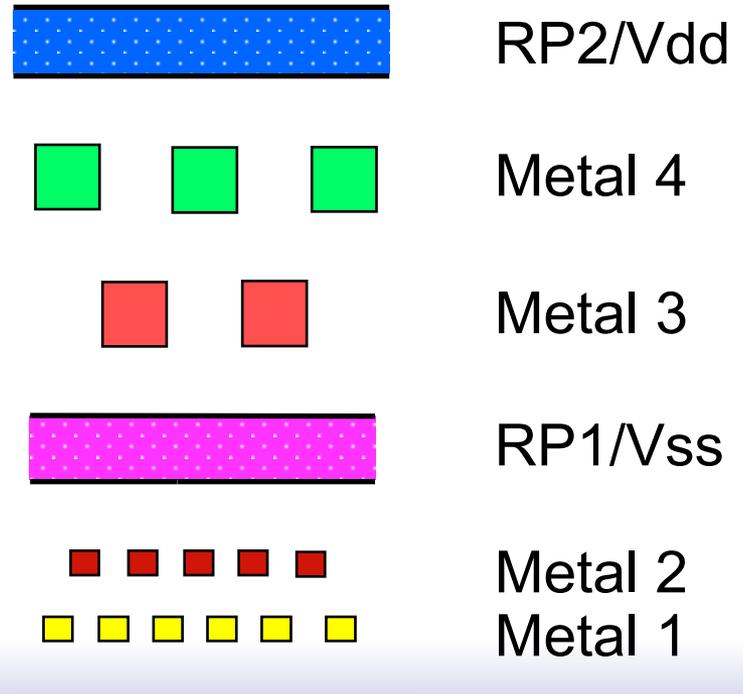
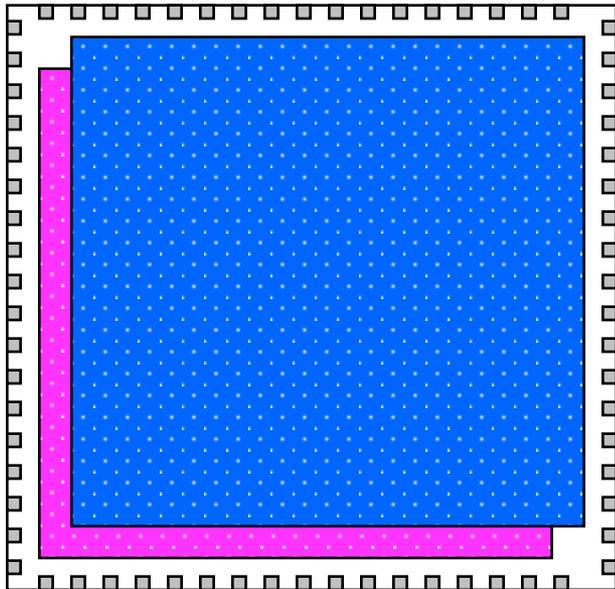
Courtesy Compaq

6 Metal Layer Approach – EV6

2 reference plane metal layers added to the technology for EV6 design

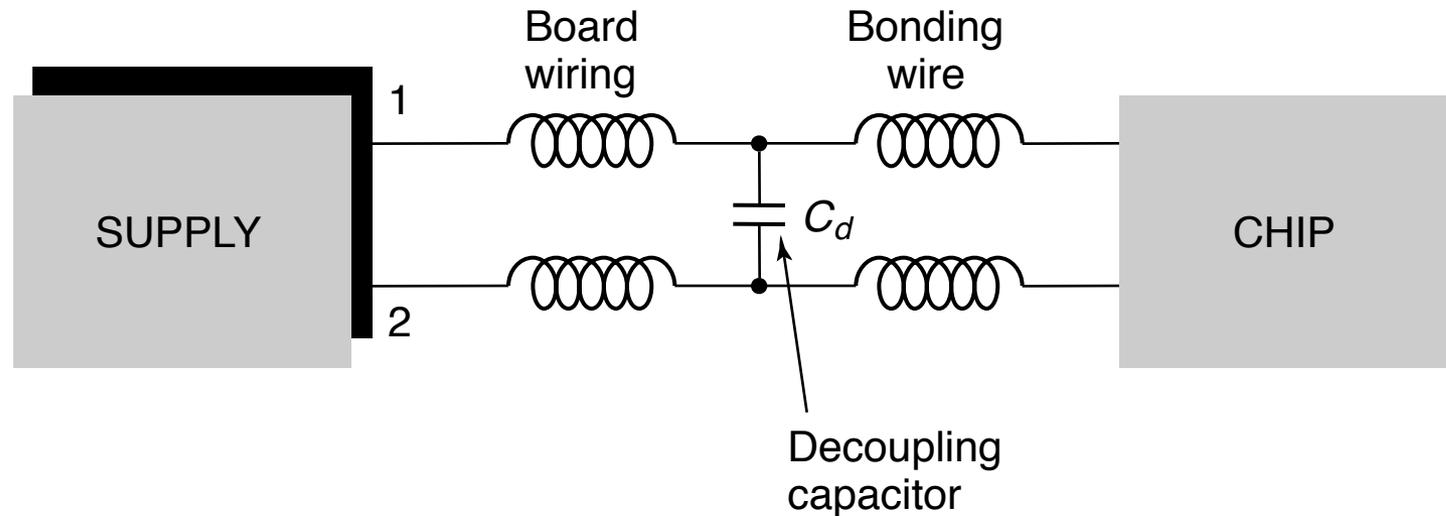
Solid planes dedicated to Vdd/Vss

Lowers on-chip inductance



Courtesy Compaq

Decoupling Capacitors

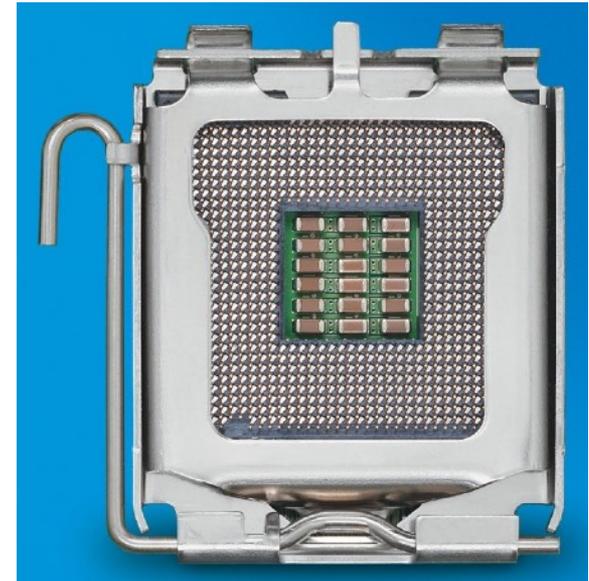


Decoupling capacitors are added:

- ❑ On the board (right under the supply pins)
- ❑ On the chip (under the supply straps, near large buffers)

Decoupling Capacitors

- Under the die

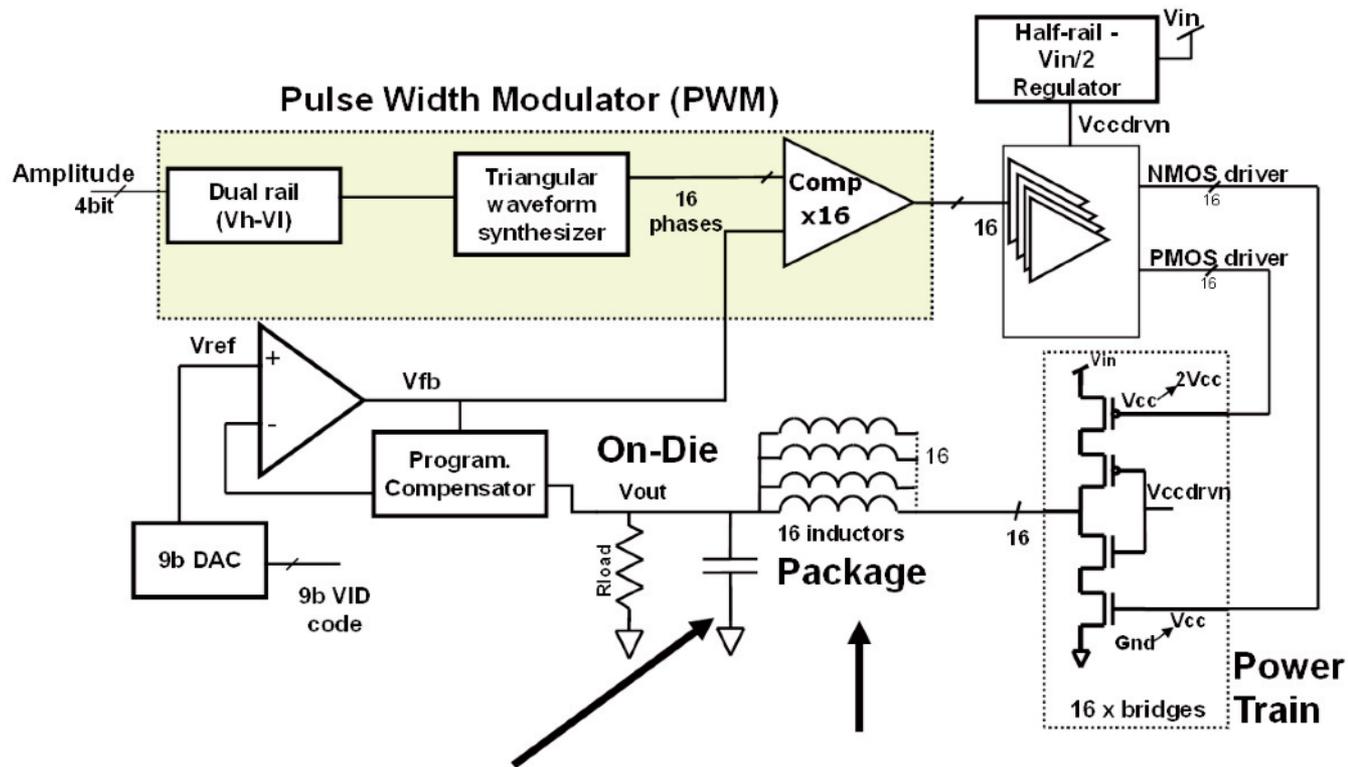


Pin Inductance Example

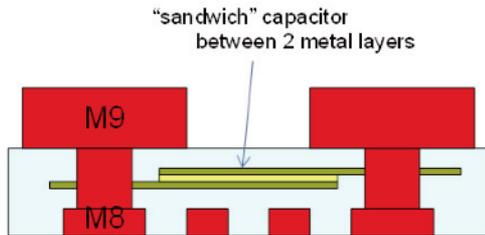
- ❑ Processor transient current is 100A in 20ps from 1V supply
- ❑ C4 bump inductance is 25pH
- ❑ How many C4 bumps do we need to get supply noise spike of less than 10%?

- ❑ With wirebond inductance of 1nH (1nH/mm) how many wirebonds are needed?

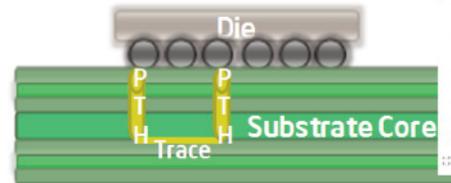
Modern Concepts: Integrated Regulators



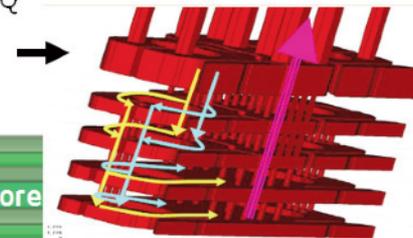
MIM Cap :density (20-30 ff/um²)



Air Core Inductors (ACI): Use pkg traces and PTH's for inductor (High Q = ~30)



ACI



□ 1.7V down to 1V, 0.1-16A

[Haswell CPU]